

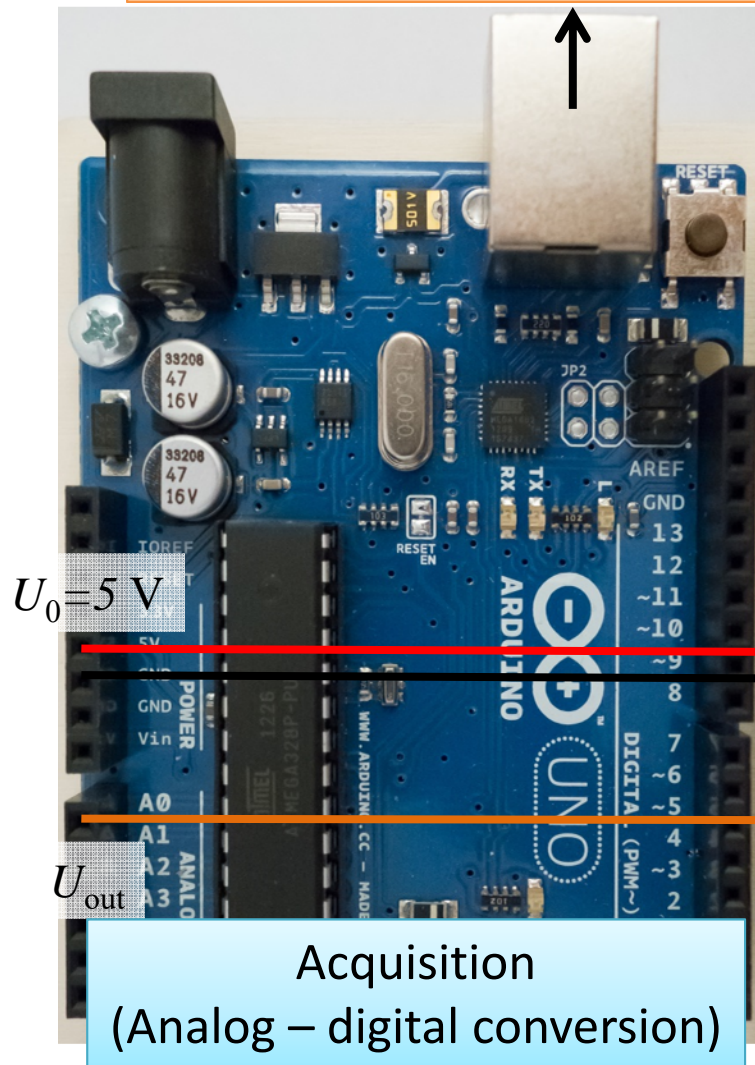
# Measurement systems

Lecturer: Andras Kis

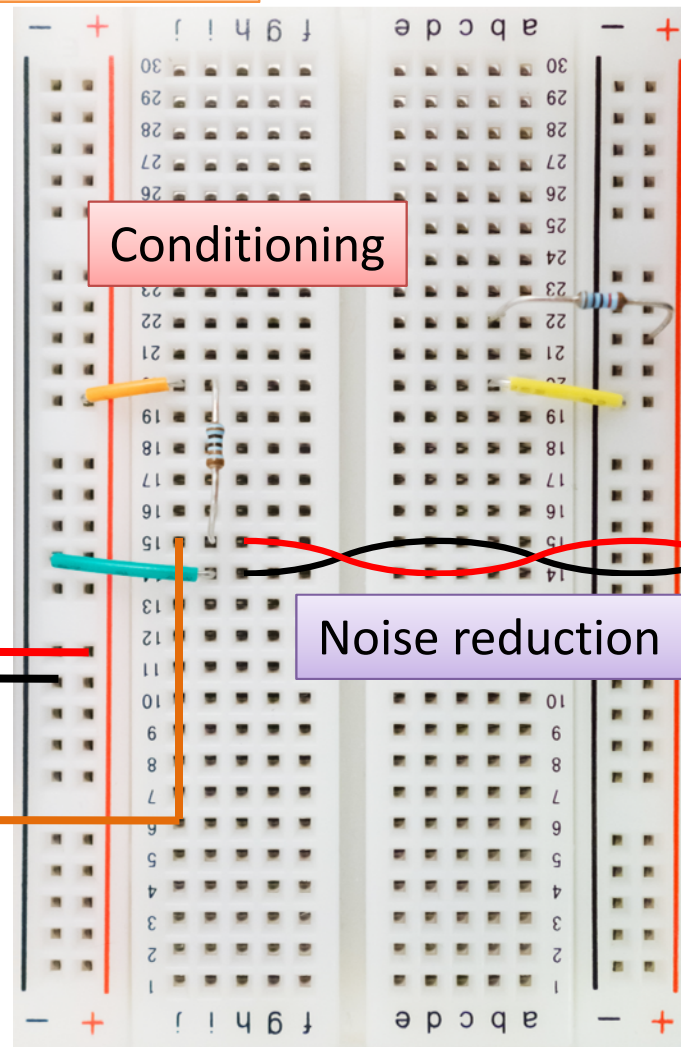
# Chapter 2: Modeling

# Measurement chain

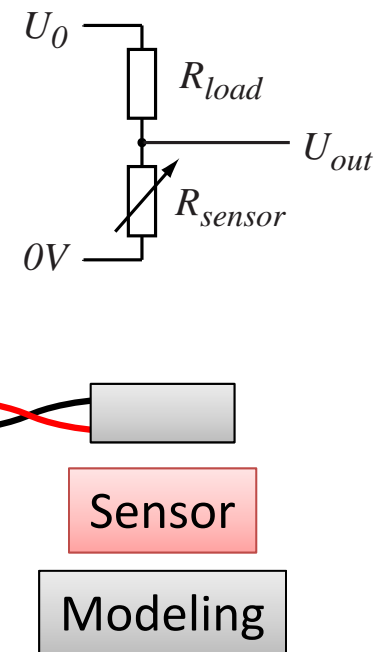
Data analysis (recording, averaging, etc.)



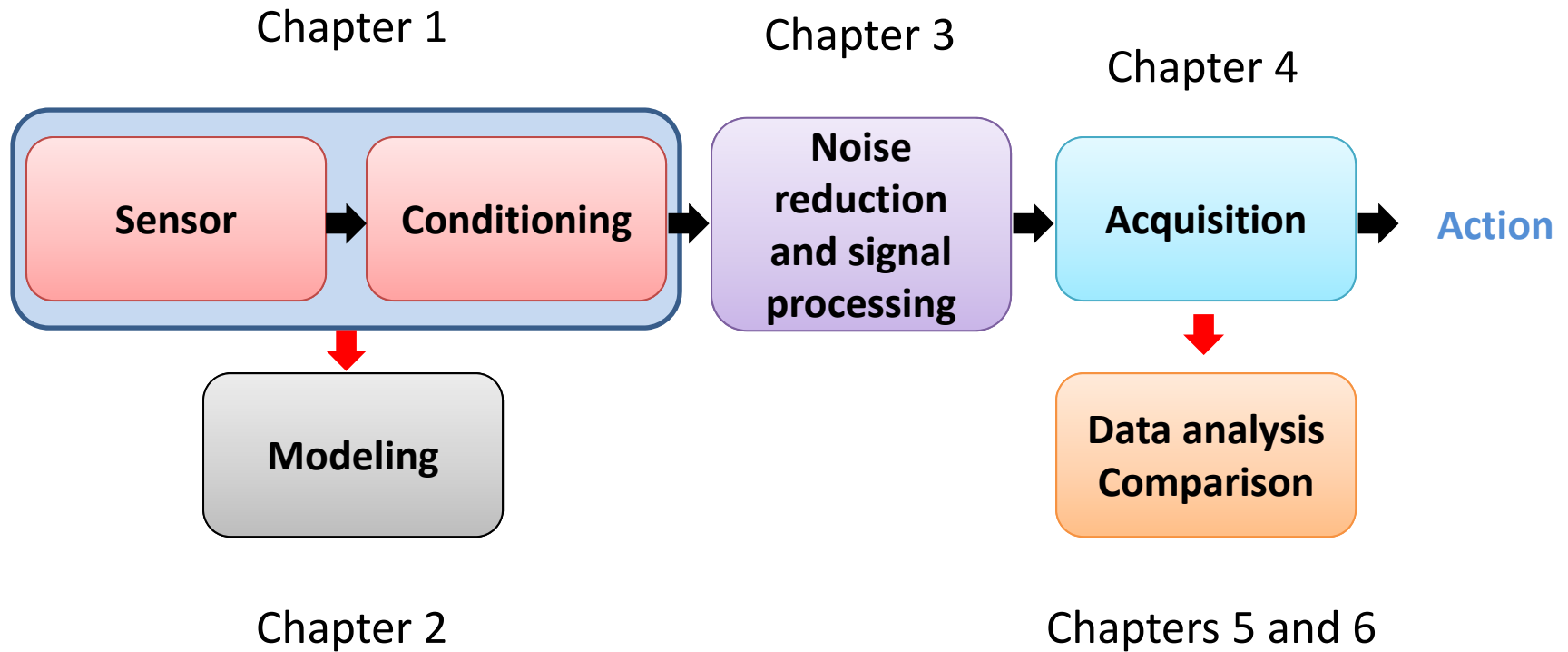
Arduino UNO board



Conditioning circuit



# Measurement chain



# Chapter 2: Modeling

- Introduction
- General model
- Static transfer
- Dynamic transfer

# What are the important parameters of a measurement system?



## SPECIFICATIONS

**Excitation:** 10 to 50 N: 5 Vdc  
≥100 N: 10 Vdc

**Output:** 10 to 50 N: 1.5 mV/V (nom)  
≥100 N: 2 mV/V (nom)

**Accuracy:** (Linearity and Hysteresis combined)  
±0.15% FSO ≤500 N  
±0.20% FSO ≥1000 N

**Repeatability:** 0.20% FSO

**5-Point Calibration:** (in tension)  
0%, 50%, 100%, 50%, 0%

**Zero Balance:** ±2% FSO

**Deflection:** 0.025 to 0.075 mm

**Operating Temp Range:**  
-54 to 121°C (-65 to 250°F)

**Compensated Temp Range:**  
16 to 71°C (60 to 160°F)

**Thermal Effects:**  
Span: ±0.009% FSO/°C  
Zero: 0.009% FSO/°C

**Safe Overload:** 150% of Capacity

**Ultimate Overload:** 300% of Capacity

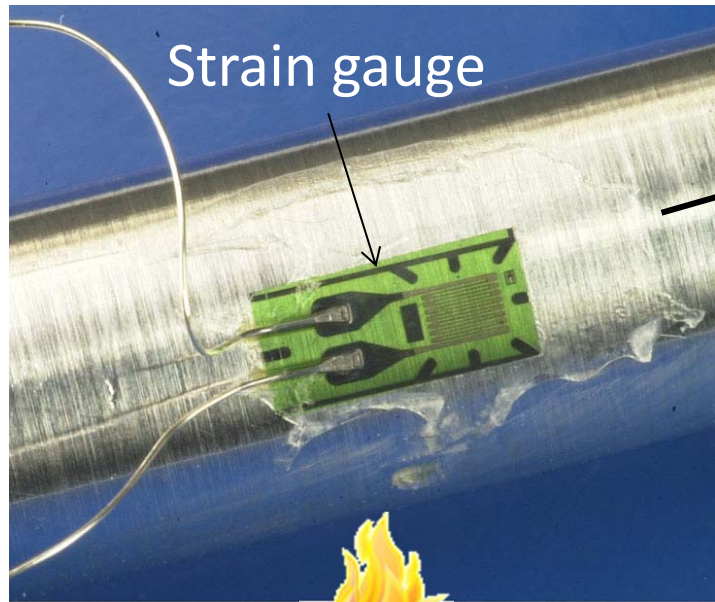
**Bridge Resistance:** 350 Ω minimum

**Construction:** Stainless Steel

**Electrical Connection:** 1.5 m (5 ft)  
4 Conductor, Shielded Cable;  
≤50N: SS Overbraided with temperature compensation board

# Force sensor

Force sensor: strain gauge on a steel bar

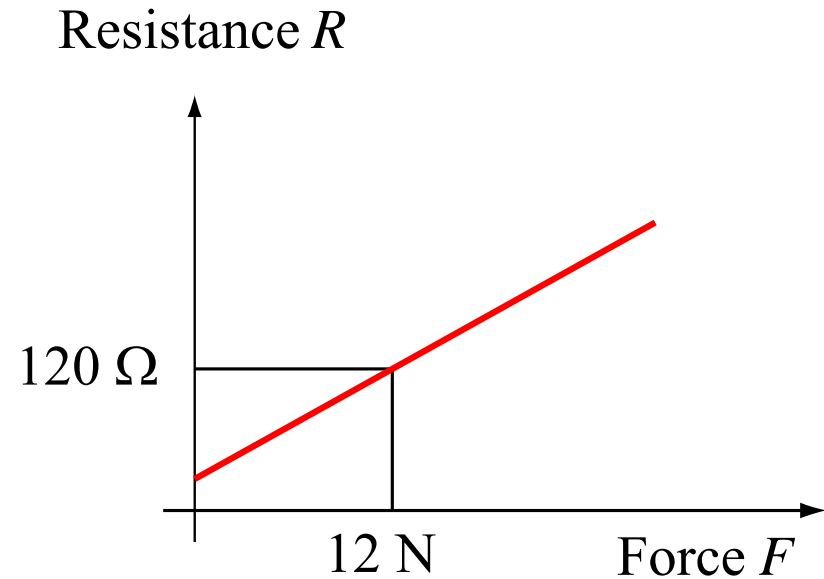


Temperature  $T$

$$\left. \frac{\Delta R}{R} \right|_F = K \varepsilon = \frac{a}{Y} F$$

sensitivity

- $a$  – proportionality factor
- $Y$  – Young's modulus
- $a/Y$  – Sensitivity



# Force sensor

- Influence of the force (measured quantity) on the sensor output:

$$\left. \frac{\Delta R}{R} \right|_F = K \varepsilon = \frac{a}{Y} F$$

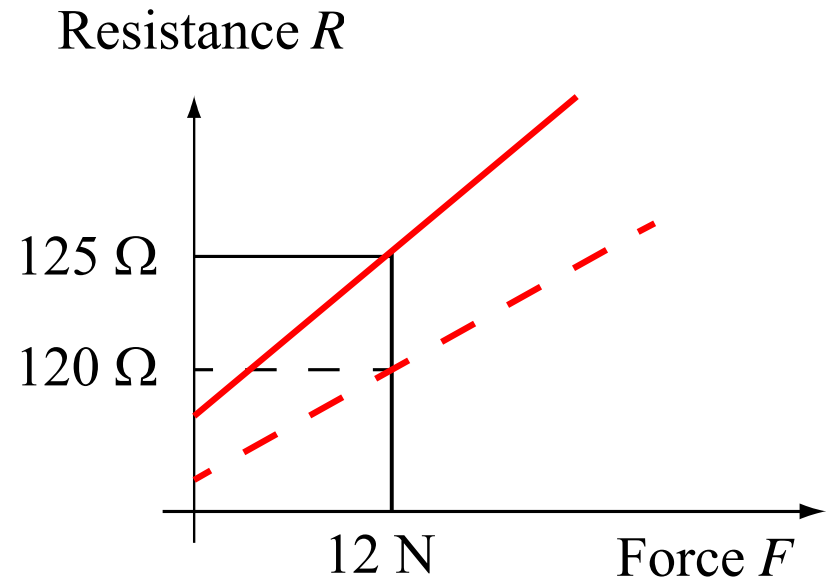
- Influence of the temperature

$$\left. \frac{\Delta R}{R} \right|_{T,offset} = \alpha_T \cdot \Delta T$$

Resistance changes with the temperature:  
**added offset on the left-hand side**

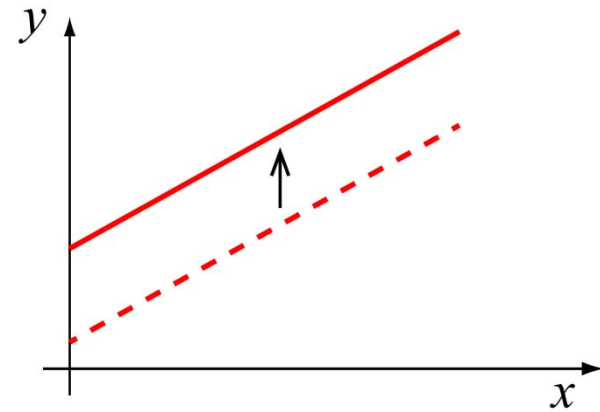
$$\left. \frac{\Delta Y}{Y} \right|_T = -\alpha_Y \Delta T, \alpha_Y = 0.26 \times 10^{-3} / ^\circ\text{C} \quad (\text{steel})$$

Material's stiffness (Young's modulus of the steel bar) changes with the temperature:  
**modified slope**

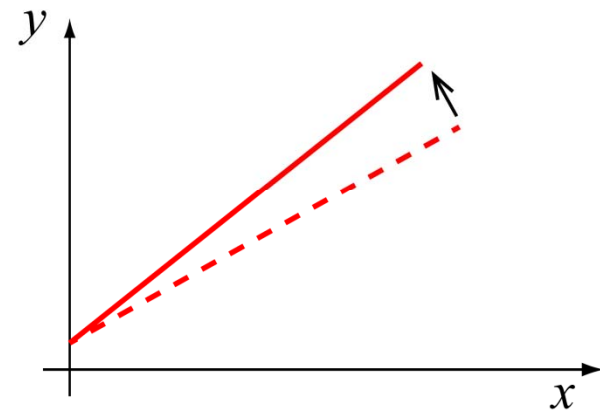




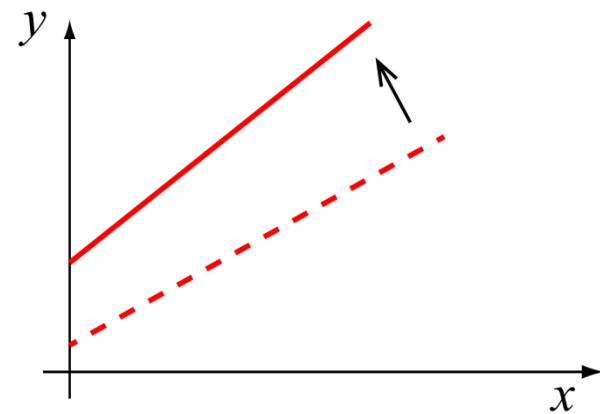
$x_i$  – interfering input  
– **adds an offset**



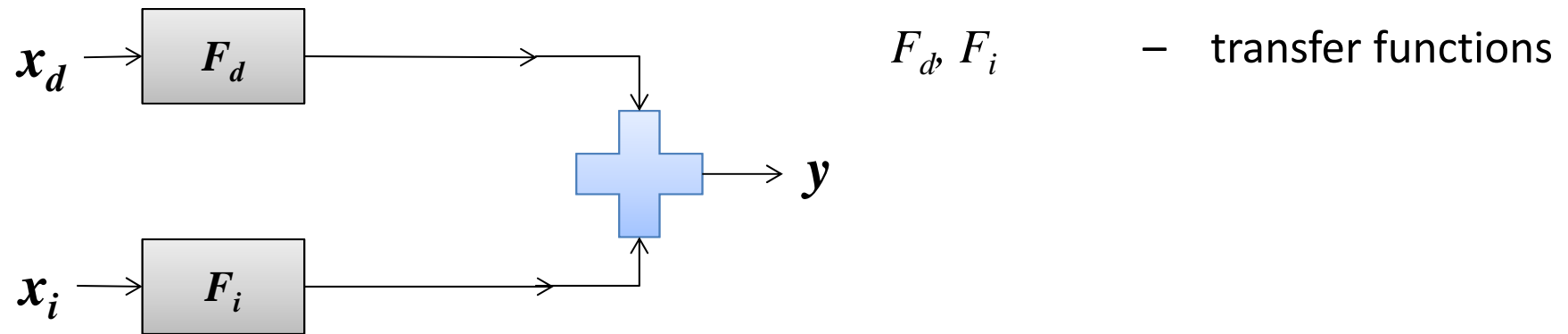
$x_m$  – modifying input  
– **changes the slope (sensitivity)**



$y$  – measured quantity



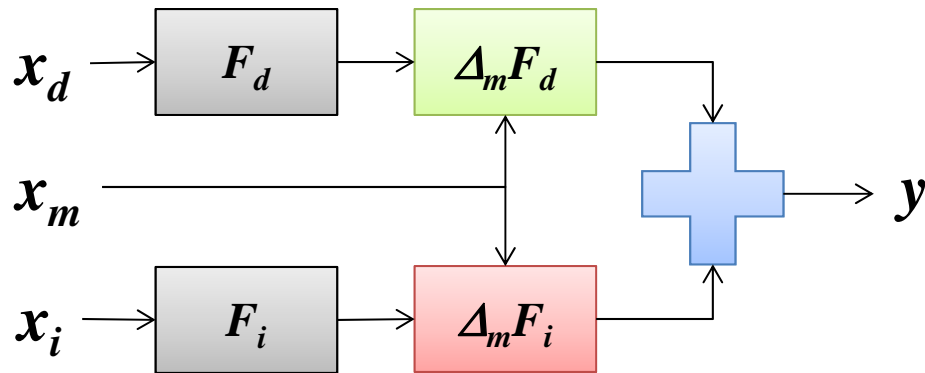
# General model



$x_d$  – desired quantity

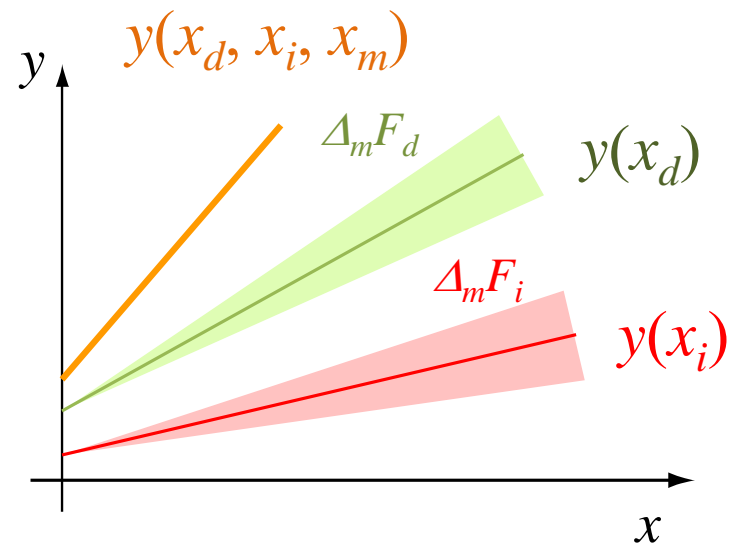
$x_i$  – interfering input

# General model



$F_d, F_i$  – transfer functions  
 $\Delta_m F_d, \Delta_m F_i$  – parameters of  $F_d, F_i$

$x_d$  – desired quantity  
 $x_m$  – modifying input  
 $x_i$  – interfering input
 } influencing inputs

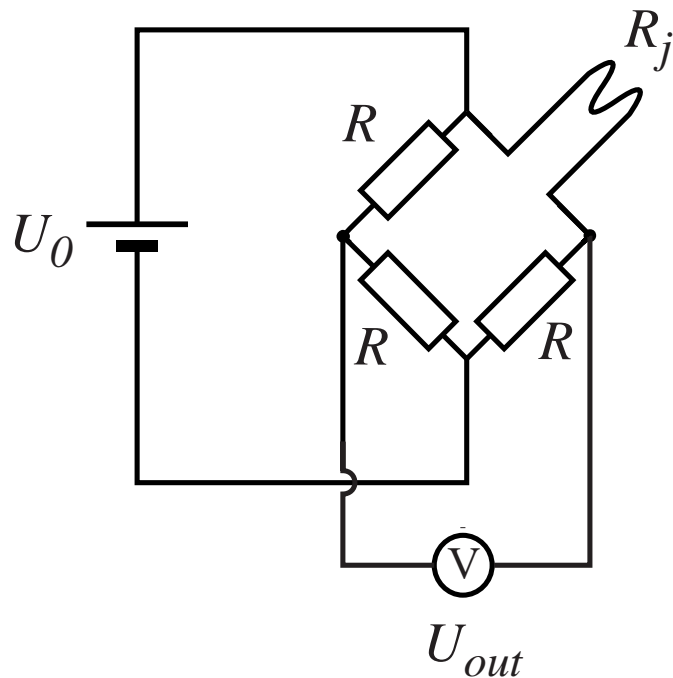


# Examples

- Temperature and a strain gauge
- Temperature and a photoresistor
- Temperature and humidity and a pressure sensor (changes in the membrane properties)

# Example

- Knowing the modifying and interfering inputs can help us compensate their influence
- Example: strain gauge



$R_j = R$  in the absence of deformation

$$\left. \frac{\Delta R_j}{R_j} \right|_F = K \varepsilon$$

$$U_{out} = \frac{\Delta R}{4R} U_0 = \frac{1}{4} K U_0 \cdot \varepsilon = S \cdot \varepsilon$$

sensitivity

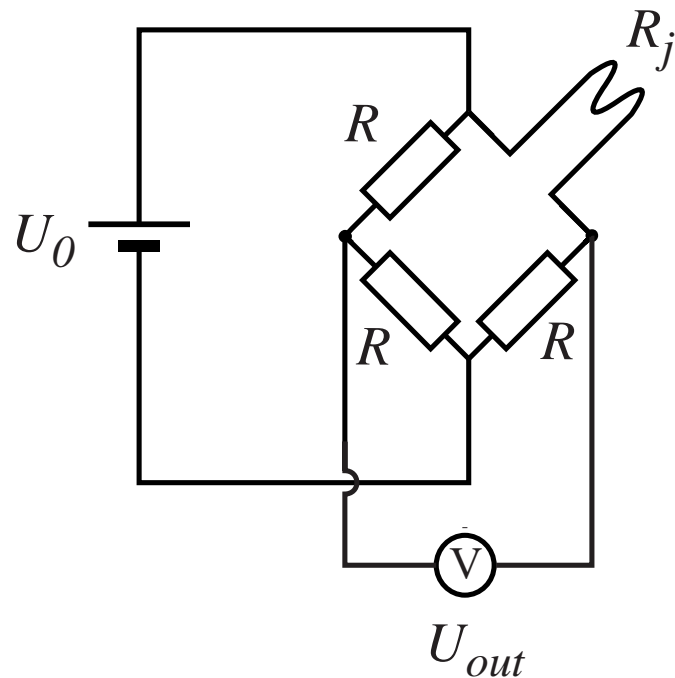
Influence of  $T$

$$\frac{\Delta R_j}{R_j} = \alpha_R \Delta T \longrightarrow U_{out,T} = \alpha_R \Delta T \frac{U_0}{4} + \frac{1}{4} K U_0 \cdot \varepsilon$$

Interfering input

# Example

- Knowing the modifying and interfering inputs can help us compensate their influence
- Example: strain gauge



Influence of  $U_0$

$$U_{out} = \frac{\Delta R}{4R} (U_0 + \Delta U_0)$$

$$\Delta S = \frac{1}{4} K \Delta U_0$$

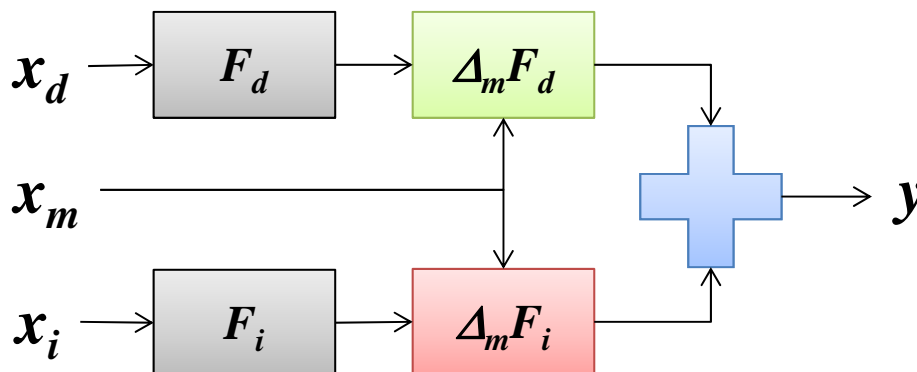
Modifying input

# Static transfer characteristics

- Acquisition of static transfer characteristics:
  - All the inputs are kept constant, except for one which is varied stepwise (static calibration)
  - Measure the output after all the transients have disappeared
  - This is called *static calibration*

- Components of the static transfer characteristics:

Range  
Sensitivity  
Offset  
Drift  
Linearity  
Hysteresis  
Repeatability  
Resolution  
Threshold  
Stability

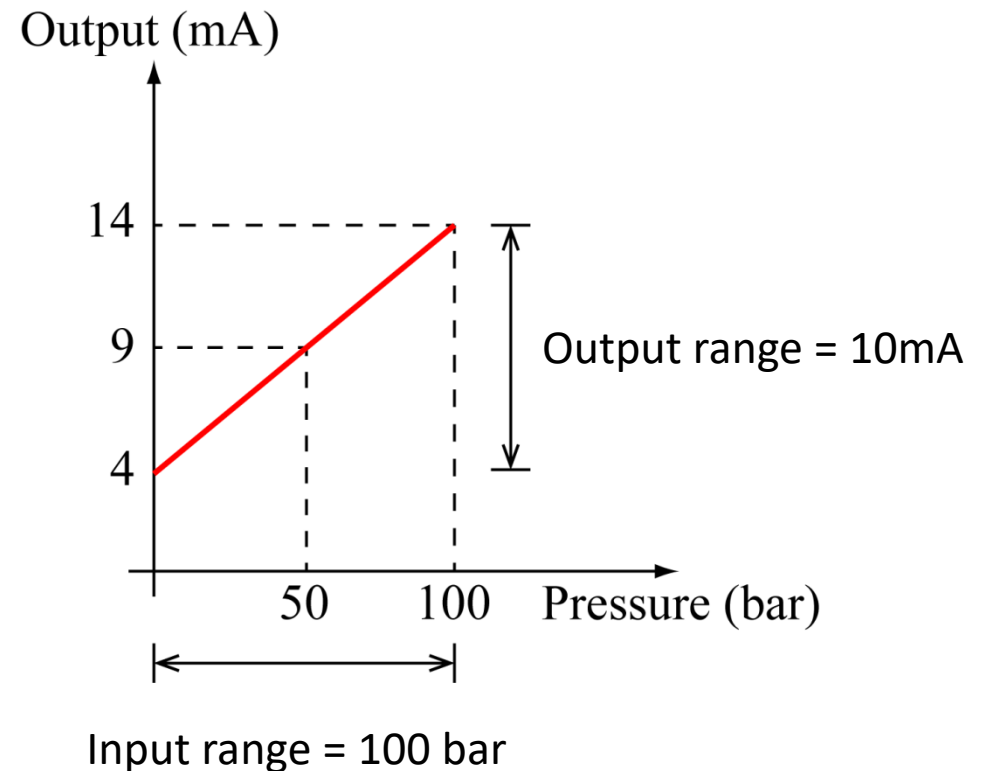


# Measurement range

- Input range (input span): the interval within which the input values can vary

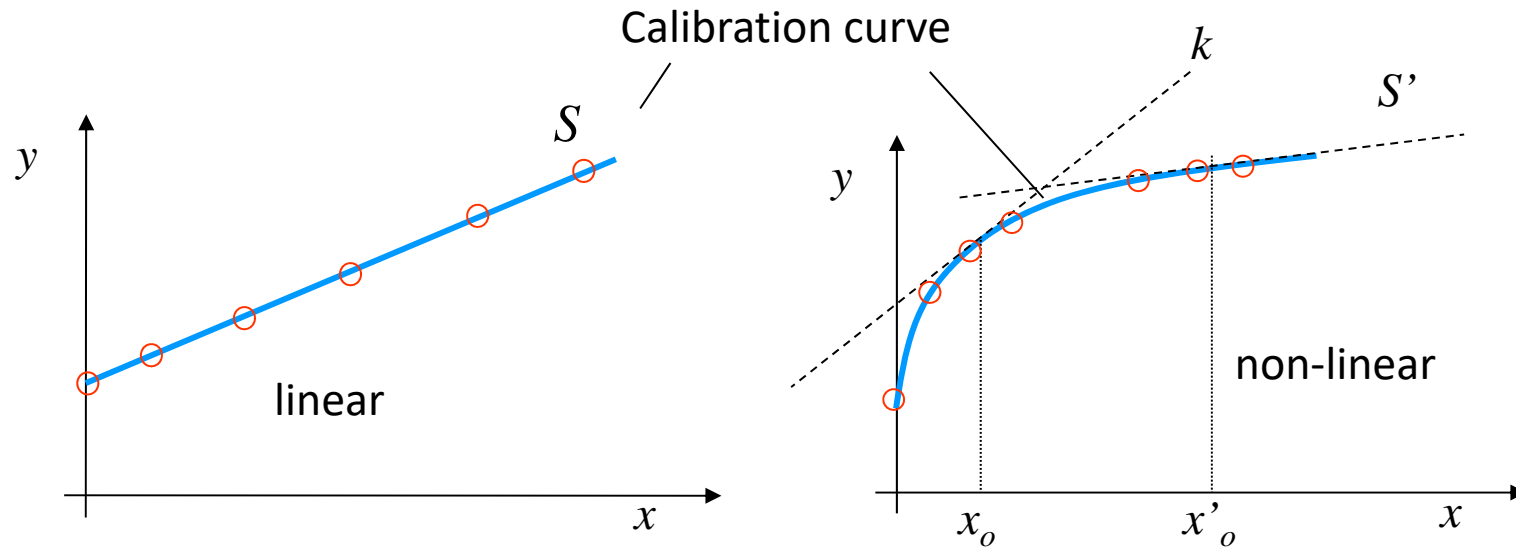
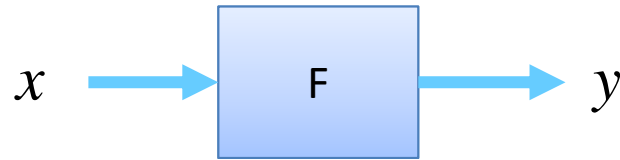
$$\text{Range} = x_{\max} - x_{\min}$$

- Output range (output span)
- Measurement range – sometimes also called full scale (FS)





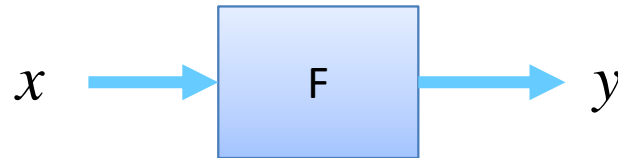
# Sensitivity



Sensitivity

$$S = \left. \frac{dy}{dx} \right|_{x=x_0}$$

# Offset

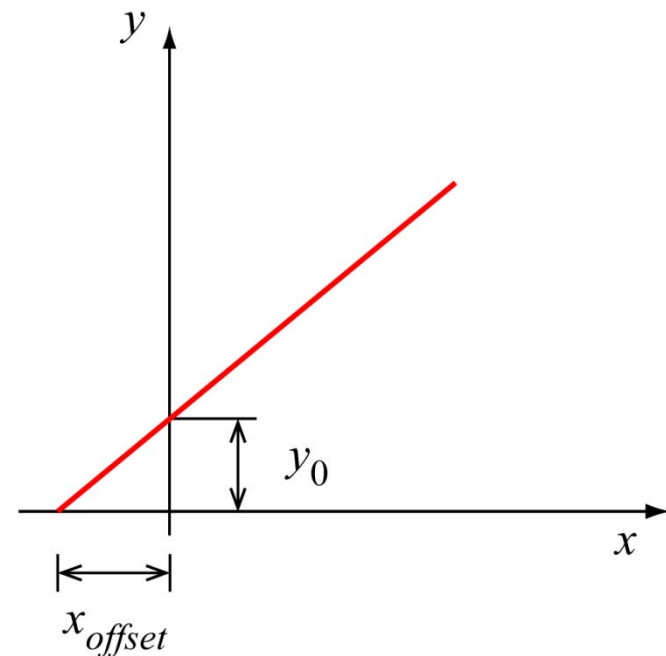


- Value of the output ( $y_0$ ) for input  $x = 0$

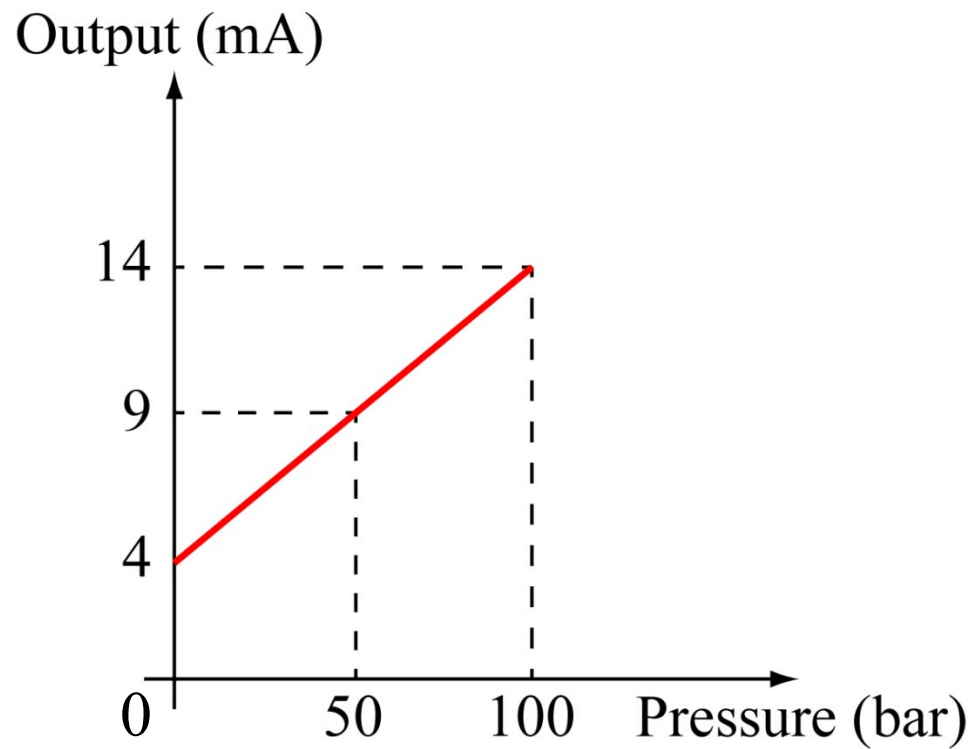
$$y = S \cdot x + y_0$$

- Error in terms of the input value:

$$x_{offset} = \frac{y_0}{S}$$



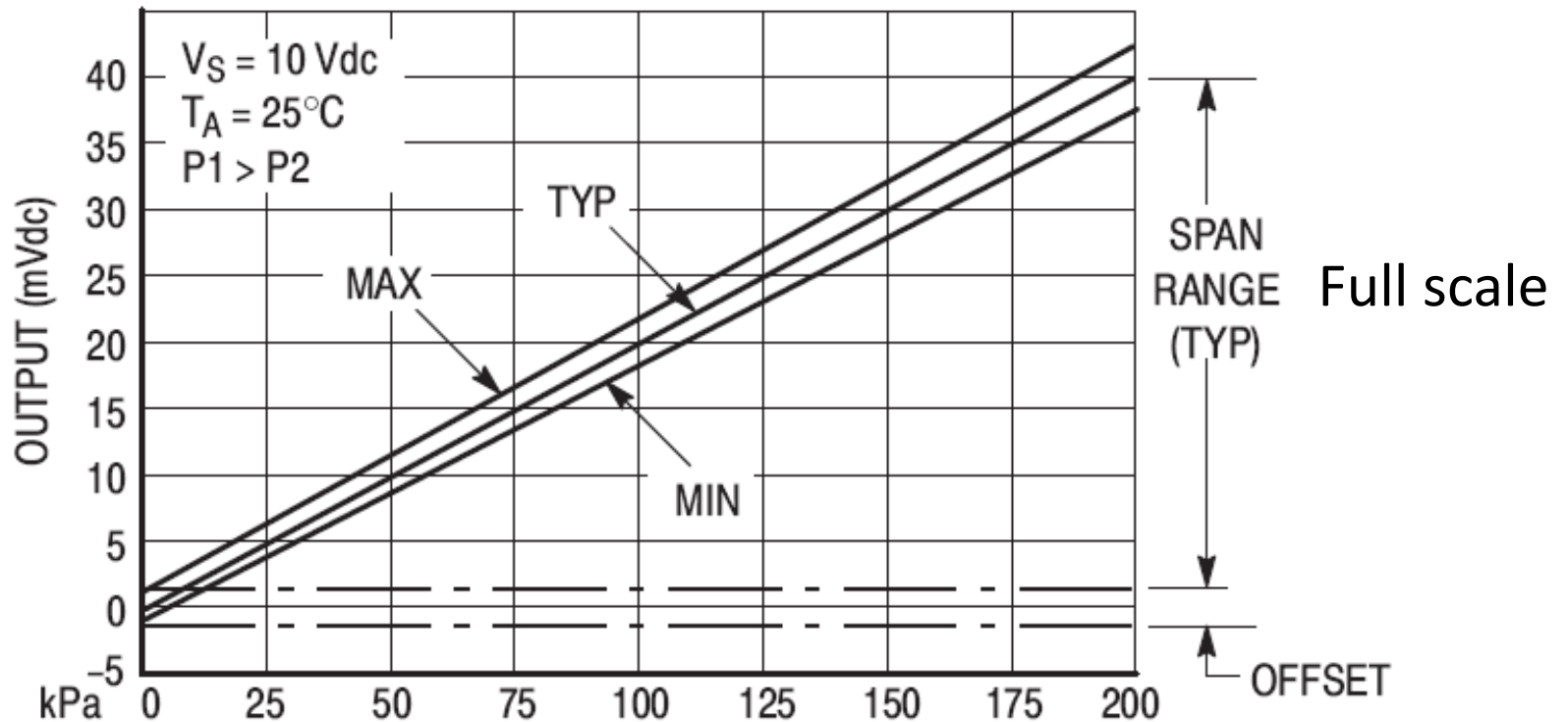
# Example: pressure sensor



Sensitivity:  $S = (14\text{mA} - 4\text{mA}) / 100 \text{ bar} = 0.1 \text{ mA/bar}$

Offset:  $y_0 = 4\text{mA} (40 \text{ bar})$

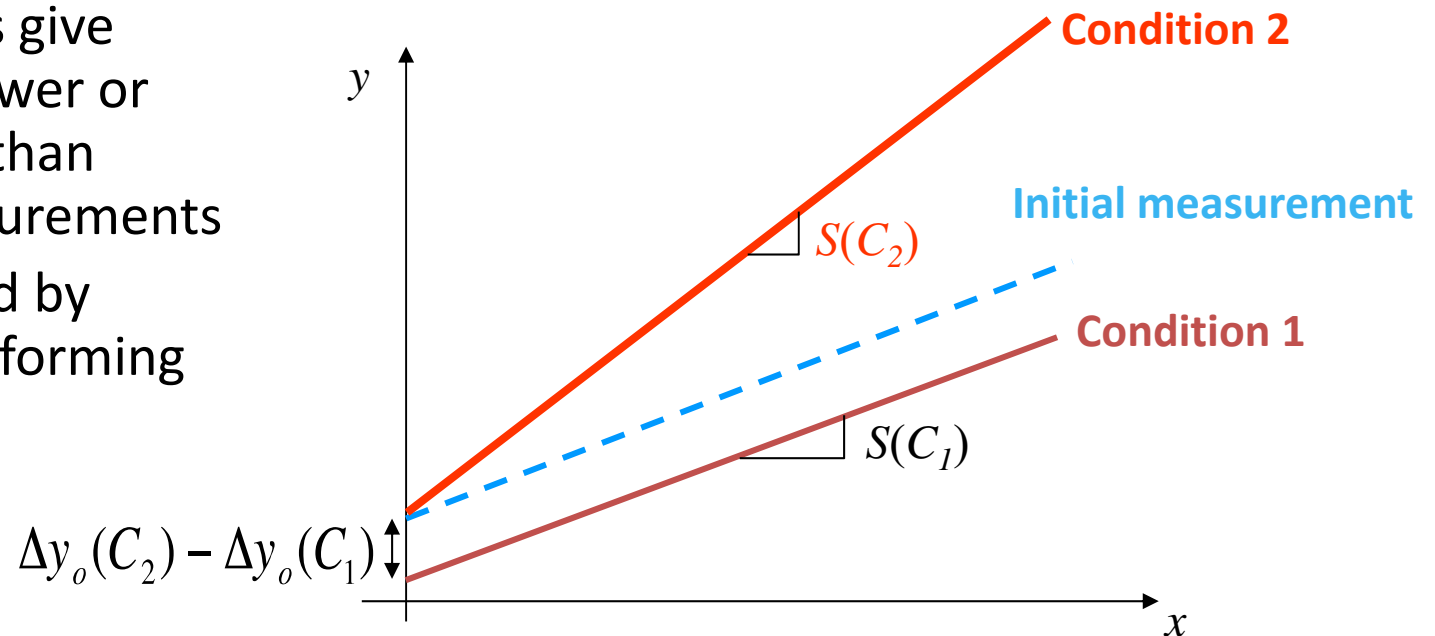
# Example: specification sheet for a pressure sensor



Pressure range	FS	0-200	kPa
Offset	$V_{off}$	$\pm 2$	mV
Sensitivity	$\Delta V/\Delta P$	0.2	mV/kPa

# Drift

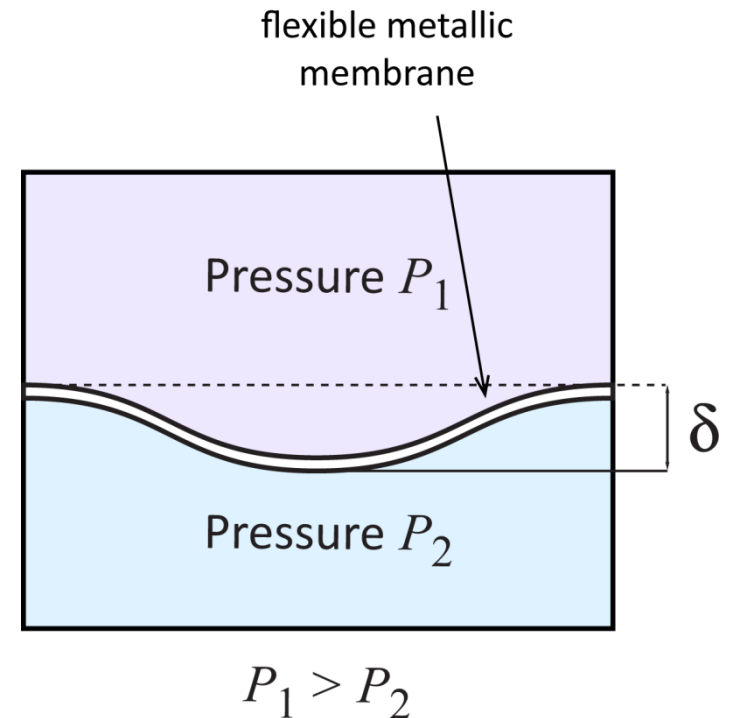
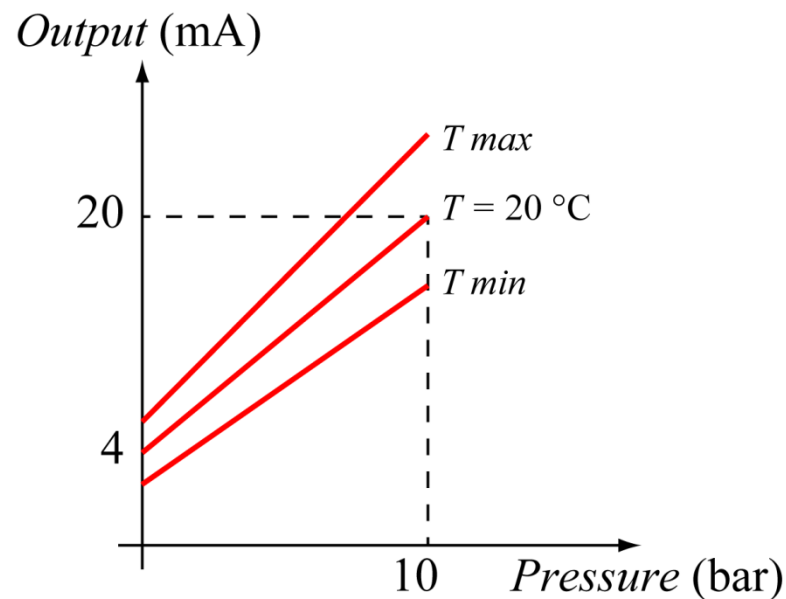
- Slow (in terms of time) variations of the sensitivity or offset
  - Example: instrument warming up
  - Repeated measurements give successively lower or higher results than previous measurements
  - Can be checked by repeatedly performing zero readings



$C_2$ : the perturbation changes the sensitivity (modifying)  
 $C_1$ : the perturbation changes the offset (interfering)

# Example of drift

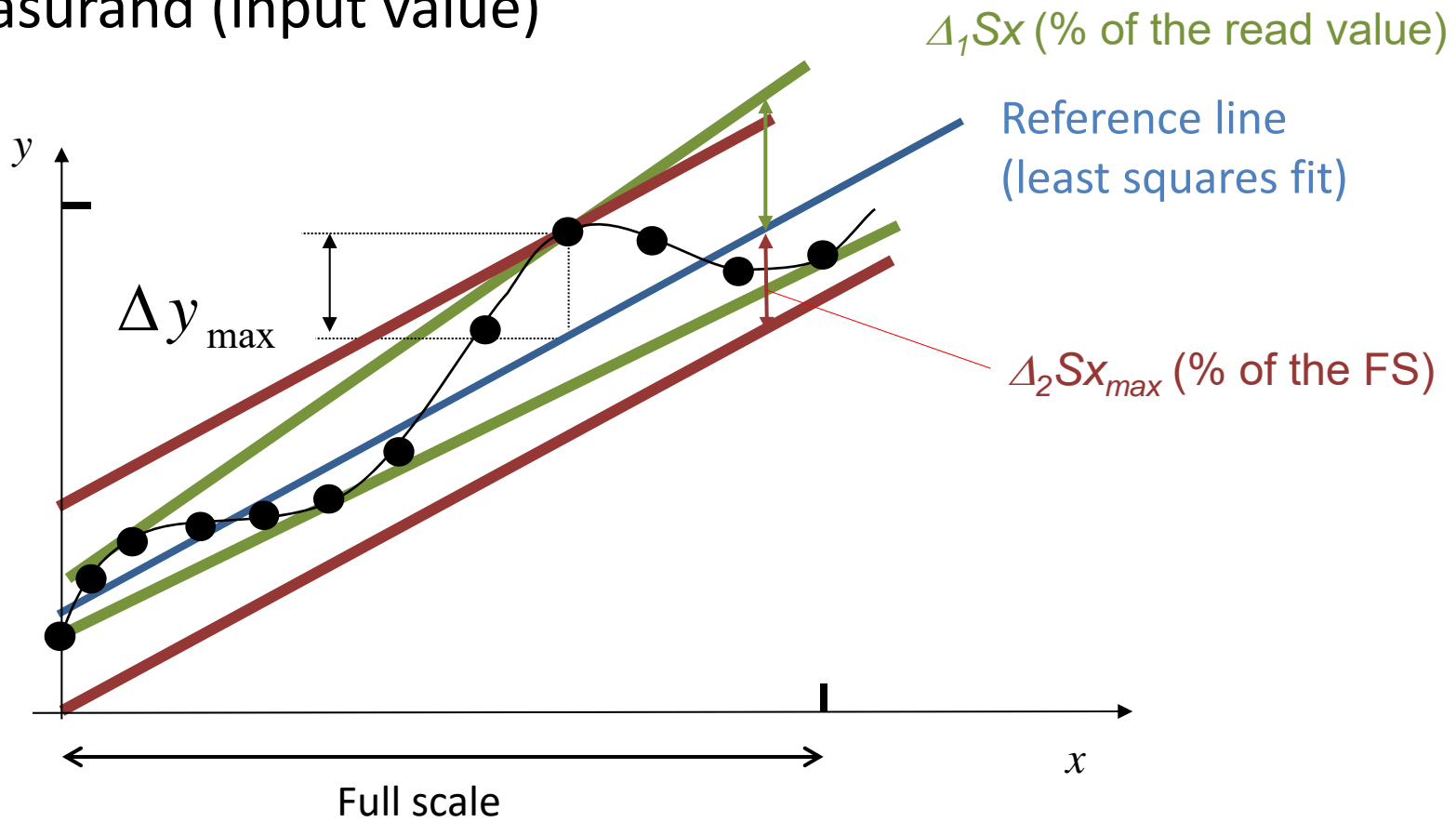
- Influence of the temperature on a pressure sensor



Offset drift: self-heating of the strain gauge (resistor)  
Sensitivity drift: heating of the membrane resulting in the change of the Young's modulus

# Linearity

- Describes in what measure the sensitivity independent of the measurand (input value)



$$y = y_0 + S \cdot x \pm \underbrace{(\Delta_1 Sx \text{ or } \Delta_2 Sx_{\max})}_{\text{whichever is bigger}}$$

# Reference line – least squares fit

- Assume

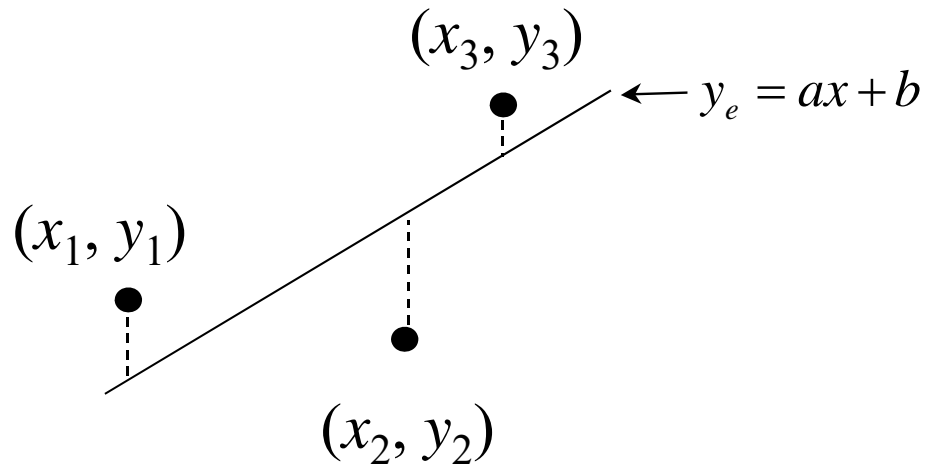
$$y_e = ax + b$$

- Minimize total distance

$$D = \sum_{i=1}^N (y_i - ax_i - b)^2$$

$$\frac{\partial D}{\partial a} = 0, \frac{\partial D}{\partial b} = 0$$

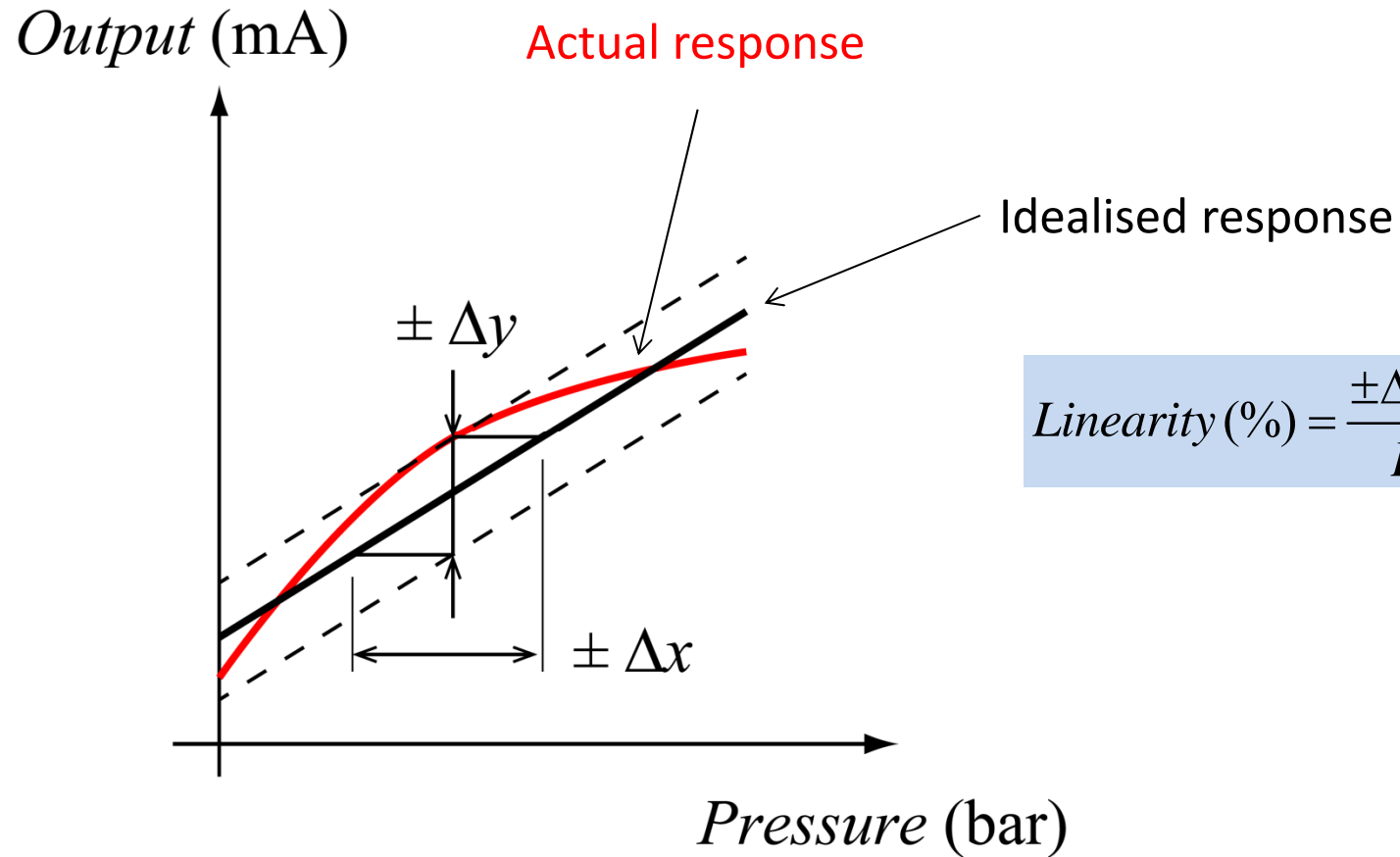
$$a = \frac{\sum_{i=1}^N x_i y_i - \frac{1}{N} \sum_{i=1}^N x_i \sum_{i=1}^N y_i}{\sum_{i=1}^N x_i^2 - \frac{1}{N} \left( \sum_{i=1}^N x_i \right)^2}$$



$$b = \bar{y} - a\bar{x} = \frac{\frac{1}{N} \sum_{i=1}^N x_i^2 \sum_{i=1}^N y_i - \frac{1}{N} \sum_{i=1}^N x_i \sum_{i=1}^N x_i y_i}{\sum_{i=1}^N x_i^2 - \frac{1}{N} \left( \sum_{i=1}^N x_i \right)^2}$$



# Example of linearity

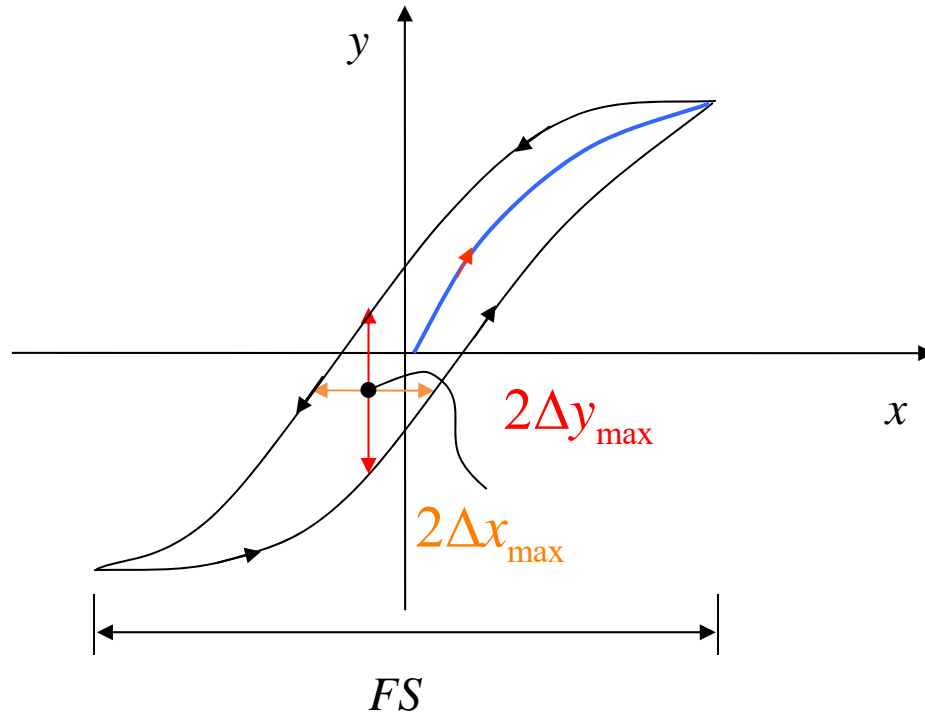


$$\text{Linearity (\%)} = \frac{\pm \Delta x_{\max}}{FS}$$

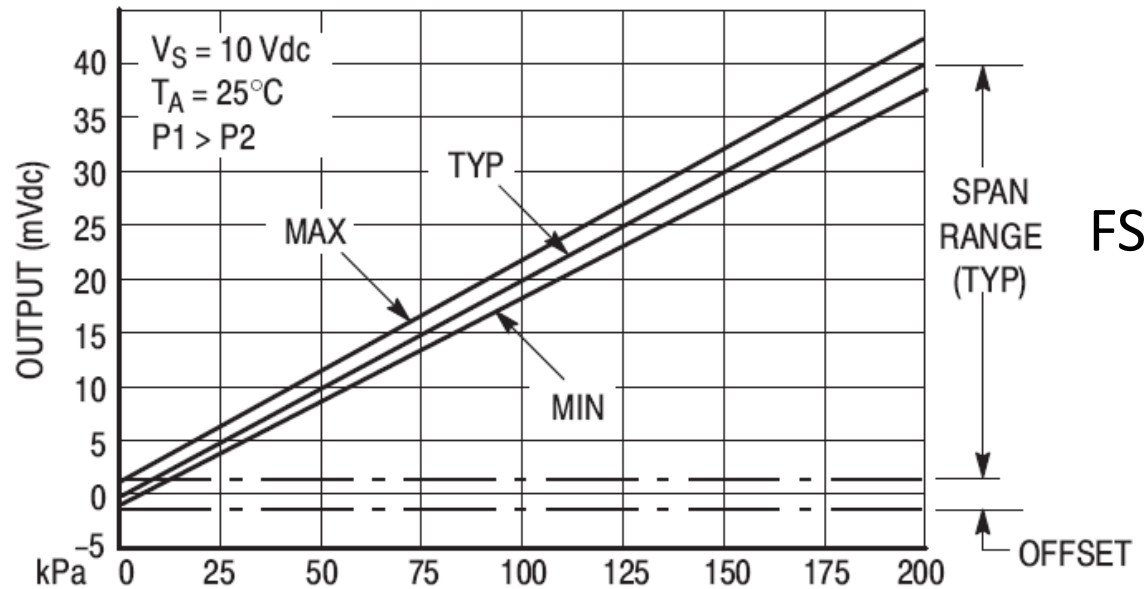
# Hysteresis

- Response depends on history
  - Magnetic polarisation
  - Piezoelectric polarisation
  - Friction

$$\text{Hysteresis (\%)} = \frac{\pm \Delta x_{\max}}{FS}$$

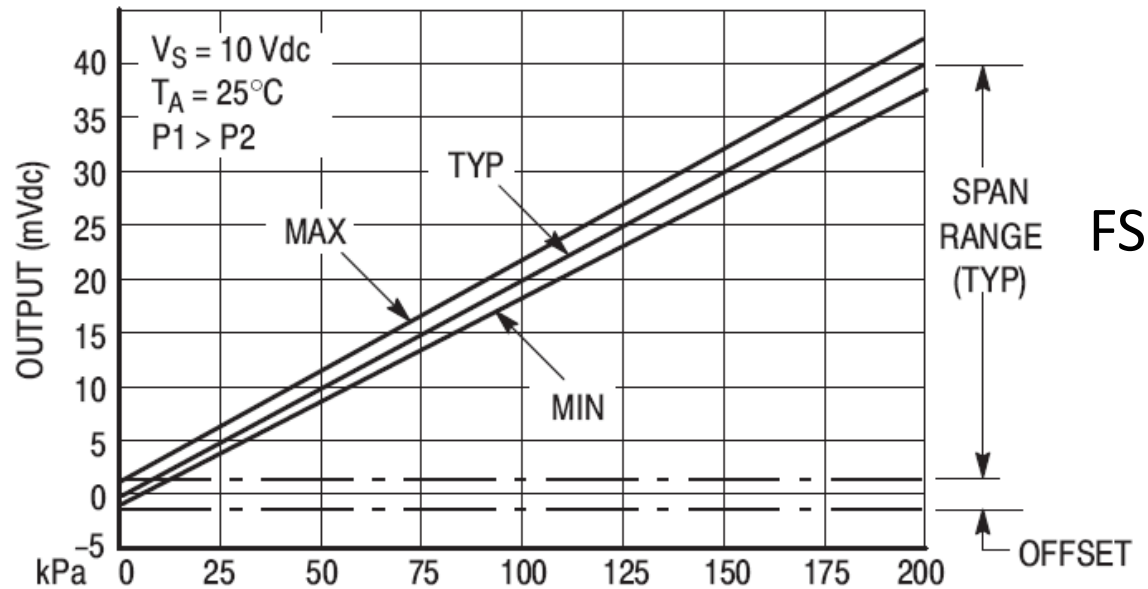


# Example: pressure sensor datasheet



Pressure range	FS	0-200	kPa
Offset	$V_{\text{off}}$	$\pm 1$	mV
Sensitivity	$\Delta V/\Delta P$	0.2	mV/kPa
Linearity		$\pm 0.5\%$	FS
Hysteresis		$\pm 0.5\%$	FS

# Example: pressure sensor datasheet



Pressure range	FS	0-200	kPa
Offset	$V_{off}$	$\pm 1$	mV
Sensitivity	$\Delta V / \Delta P$	0.2	mV/kPa
Temperature effect on FS (0 to 50°C, $T_{ref}=25^\circ\text{C}$ )	$T_{FS}$	$\pm 2\%$	FS
Temperature effect on Offset (0 to 50°C, $T_{ref}=25^\circ\text{C}$ )	$T_{OFF}$	$\pm 1$	mV

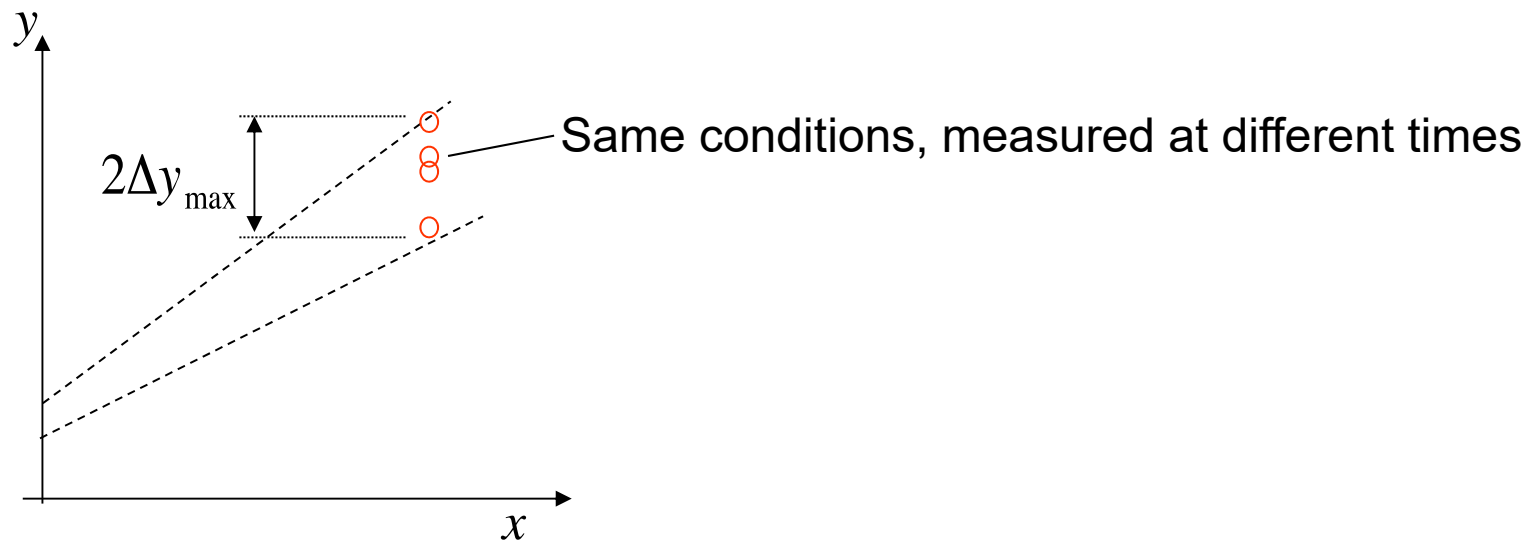
$$Err_{T,FS} = \pm 2 \cdot 200 / 100 = 4 \text{ kPa}$$

$$Err_{T,OFF} = \pm 1 / 0.2 = 5 \text{ kPa}$$

# Repeatability

- Distribution of successive measurements of  $y$  under the same conditions

$$\text{Repeatability (\%)} = \frac{\pm \Delta x_{\max}}{FS}$$



# Stability

- The ability to maintain a response  $y$  for a constant  $x$  and during a given time period

Pressure range	FS	0-200	kPa
Offset	$V_{off}$	$\pm 1$	mV
Sensitivity	$\Delta V/\Delta P$	0.2	mV/kPa
Offset Stability		$\pm 0.5\%$	FS

$$\text{Err}_{\text{Stab}} = \pm 0.5 \cdot 200/100 = \pm 1 \text{ kPa}$$

# Maximal and probable error

- Maximal error

$$Error_{\max} = \pm \sum_i |\Delta x_i|$$

- Probable error

$$Error_{\text{probable}} = \pm \sqrt{\sum_i \Delta x_i^2} = \pm \sigma$$

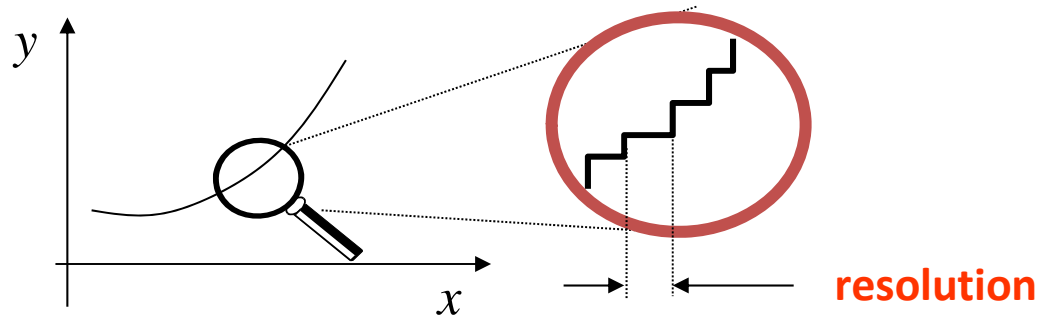
65% probability the actual error is within  $[-\sigma, +\sigma]$

98% probability the actual error is within  $[-2\sigma, +2\sigma]$

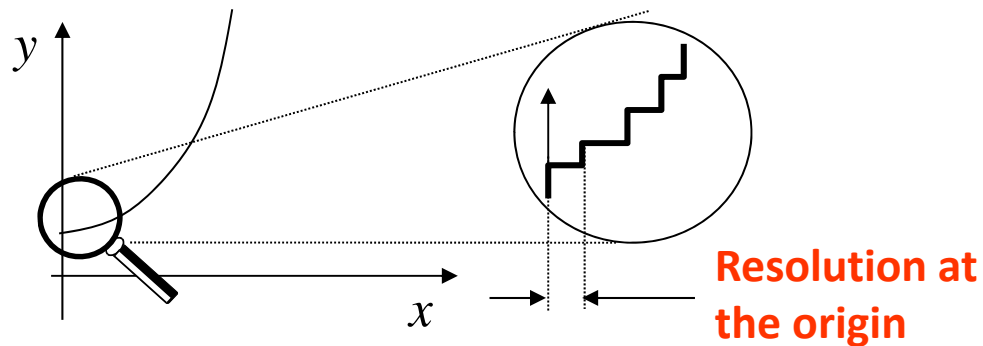
99% probability the actual error is within  $[-3\sigma, +3\sigma]$

# Resolution and threshold

- Resolution – the smallest detectable change of the input value



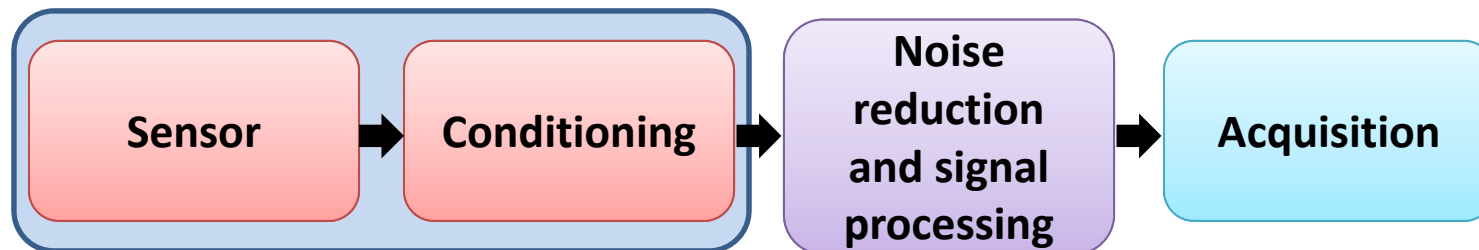
- Threshold – resolution at the origin (input = 0)





# Transfer characteristics of conditioning circuits

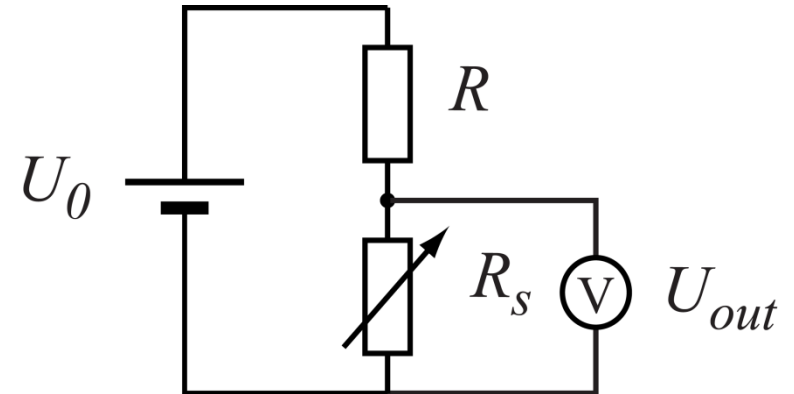
- A measurement system is not just the sensor but the entire measurement chain
- In order to determine the global transfer characteristics, one must take into account also the transfer characteristics of conditioning circuits
- Achieving the highest sensitivity of the circuit is a common design goal



# Example: voltage divider

$$U_{out} = U_0 \frac{R_s}{R_s + R}$$

$$\begin{aligned} U_{out} + \Delta U_{out} &= U_0 \frac{R_s + \Delta R_s}{R_s + \Delta R_s + R} = \\ &= U_0 \frac{R_s + \Delta R_s}{R_s + R} \frac{1}{1 + \frac{\Delta R_s}{R_s + R}} \end{aligned}$$



For  $\Delta R_s \ll R + R_s$

$$U_{out} + \Delta U_{out} = U_0 \frac{R_s + \Delta R_s}{R_s + R} \left( 1 - \frac{\Delta R_s}{R_s + R} \right)$$

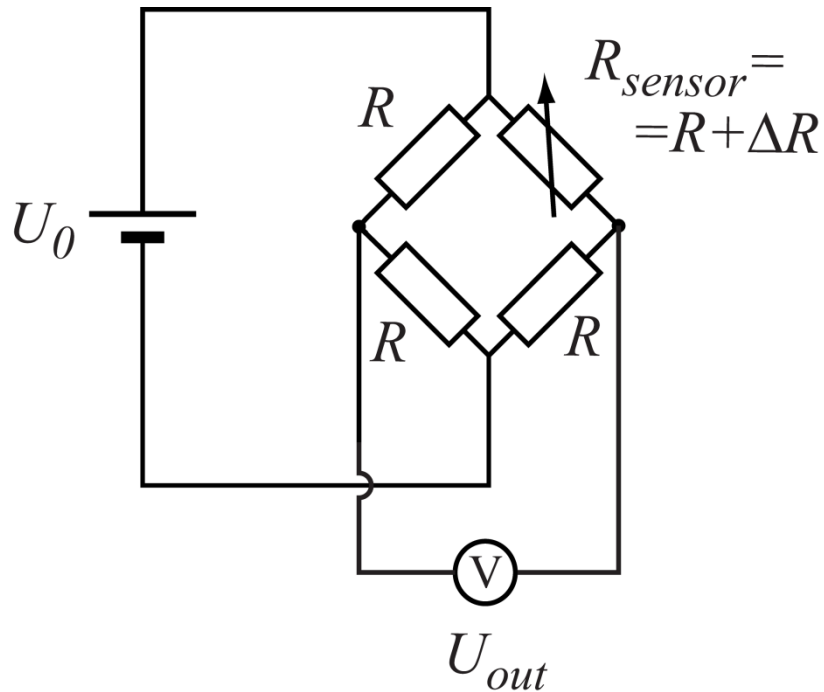
Linear with  $\Delta R_s$



$$\Delta U_{out} = U_0 \frac{R_s + \Delta R_s}{R_s + R} \left( 1 - \frac{\Delta R_s}{R_s + R} \right) - U_0 \frac{R_s}{R_s + R} = \frac{U_0 R}{(R_s + R)^2} \Delta R_s$$

Max sensitivity for  $R = R_s$ . In that case  $\Delta U_{out} = U_0 \frac{\Delta R_s}{4R}$

# Example: Wheatstone bridge

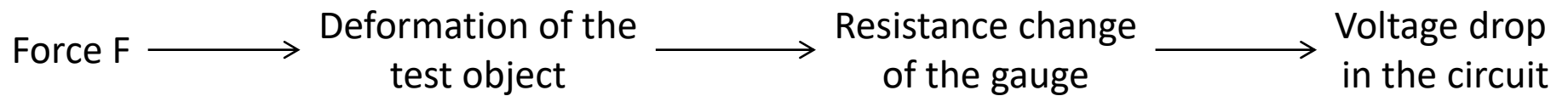
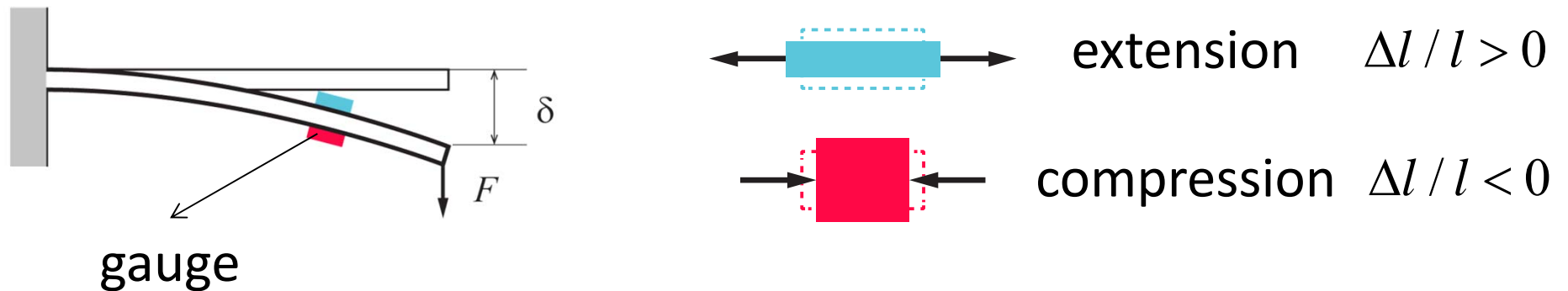


$$\begin{aligned} U_{out} &= \frac{1}{2} U_0 - \frac{R}{2R + \Delta R} U_0 \\ &= \frac{\Delta R}{4(R + \frac{\Delta R}{2})} U_0 \\ &\approx \frac{\Delta R}{4R} U_0 \end{aligned}$$

- No power supply noise for a balanced bridge
- The effect of temperature can be compensated by choosing resistors with the same temperature coefficient as the sensor

# Force sensor (repeated from Ch 1)

- Based on a strain sensor attached to a test object

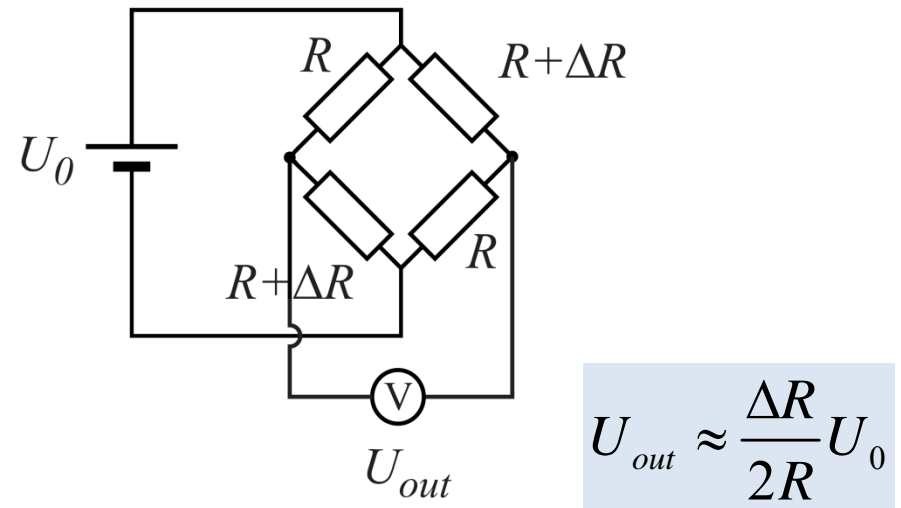
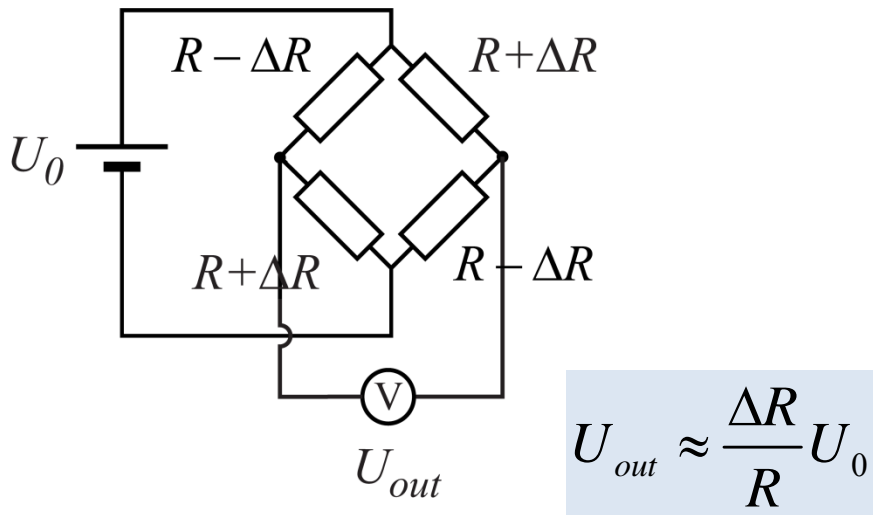
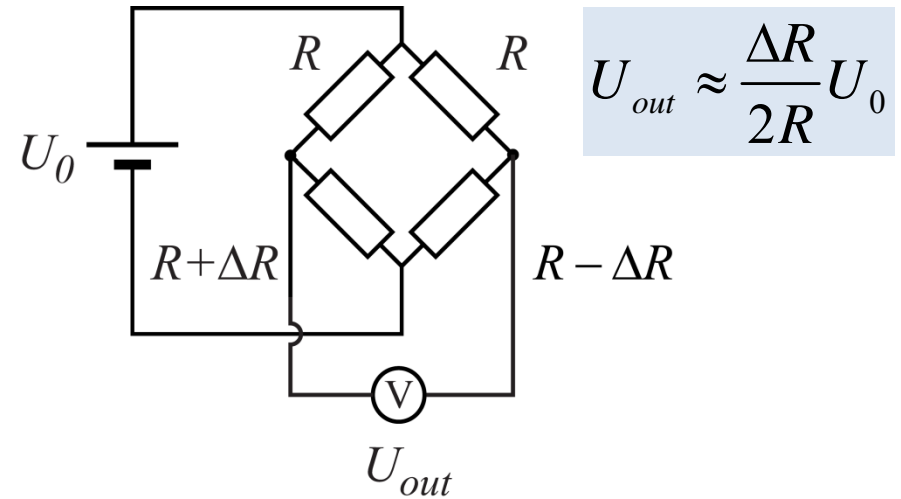
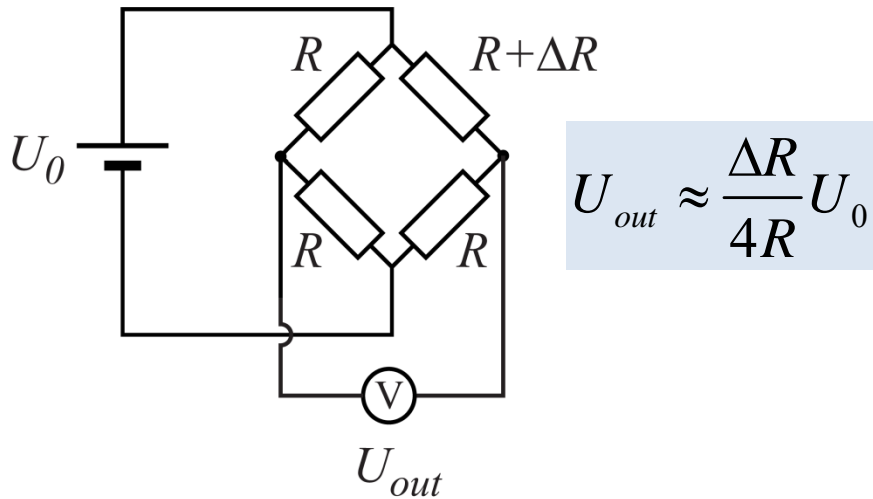


$$\frac{\Delta l}{l} = \frac{F}{A \cdot Y}$$

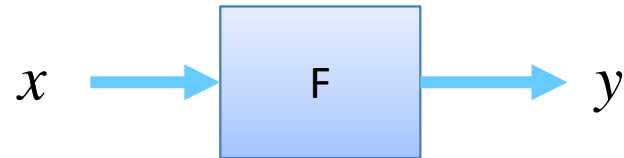
$$\frac{\Delta R}{R} = K \frac{\Delta l}{l}$$

$$\frac{\Delta U}{U} = \frac{\Delta R}{R} I$$

# Wheatstone bridge – sensitivity optimisation

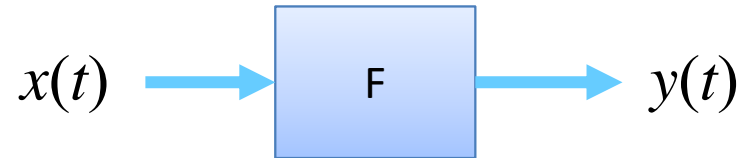


# Dynamic transfer characteristics



- Identification of the system order
- Calculating sensitivity
- Time-dependent response
- Frequency-dependent response

# Dynamic transfer characteristics

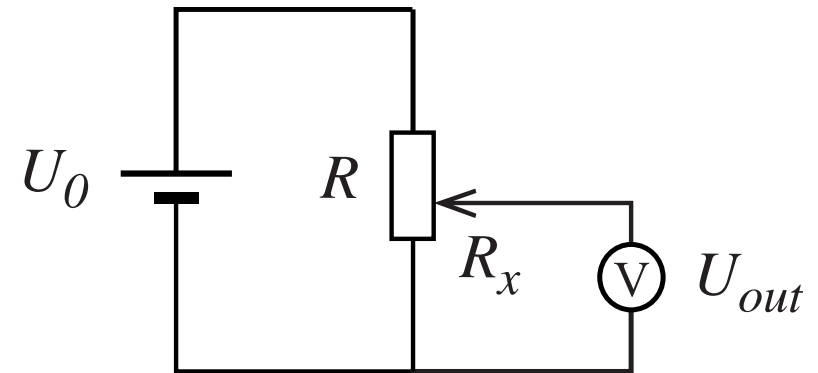


- A time-dependent input will result in a time-dependent output
- This can be described by an ordinary differential equation

$$a_n \frac{d^n y}{dt^n} + a_{n-1} \frac{d^{n-1} y}{dt^{n-1}} + \dots + a_1 \frac{dy}{dt} + a_0 y = x(t) \quad n: \text{order}$$

- Order 0:  $y(t) = S \cdot x(t)$   $S$ : sensitivity
- 1<sup>st</sup> order:  $\tau \frac{dy}{dt} + y = S \cdot x$   $\tau$ : time constant
- 2<sup>nd</sup> order:  $\frac{1}{\omega_0^2} \frac{d^2 y}{dt^2} + \frac{2\xi}{\omega_0} \frac{dy}{dt} + y = S \cdot x$   $\omega_0$ : undamped frequency  
 $\xi$ : damping factor

# Zero-order system: potentiometer



$$U_{out} = \frac{R_x}{R} U_0 = \frac{\rho \cdot \ell_x / A}{\rho \cdot \ell / A} U_0$$
$$= \frac{\ell_x}{\ell} U_0 = S \cdot \ell_x$$

The model neglects:

- induced EMF in the output loop ( $dx/dt$ )
- inductance of the potentiometer
- mechanical properties: mass of the sliding part, friction

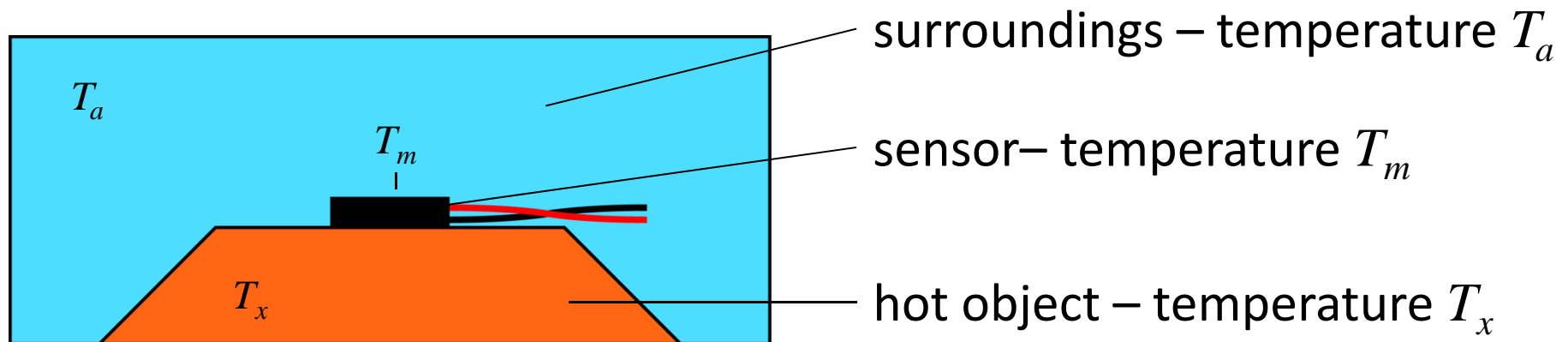
$\ell_x$  : length of section  $x$   
 $\ell$  : total length  
 $A$  : wire cross-section



# 1<sup>st</sup> order system

$$\tau \frac{dy}{dt} + y = S \cdot x \quad \tau: \text{time constant}$$

- Example: temperature measurements



Heating power for object  $\rightarrow$  sensor

$$P_x = G_{xm} (T_x - T_m)$$

Heating power for surroundings  $\rightarrow$  sensor

$$P_a = G_{am} (T_a - T_m)$$

$G_{xm}$ : heat conductivity for the sensor/object interface

$G_{am}$ : heat conductivity for the sensor/ambient interface

# 1<sup>st</sup> order system

$$\frac{dQ_m}{dt} = C \frac{dT_m}{dt}$$

$C$  : heat capacity of the sensor

$Q_m$  : amount of heat received by the sensor

$$P_a + P_x = \frac{dQ_m}{dt}$$

$$G_{am}(T_a - T_m) + G_{xm}(T_x - T_m) = C \frac{dT_m}{dt}$$

$$\tau \frac{dy}{dt} + y = S \cdot x$$

$$\frac{C}{G_{am} + G_{xm}} \frac{dT_m}{dt} + T_m = \frac{G_{xm} T_x}{G_{am} + G_{xm}} + \frac{G_{am} T_a}{G_{am} + G_{xm}}$$

← Interfering input

$$\tau = \frac{C}{G_{xm} + G_{am}}$$

$$S = \frac{G_{xm}}{G_{am} + G_{xm}}$$

Solution of the equation:

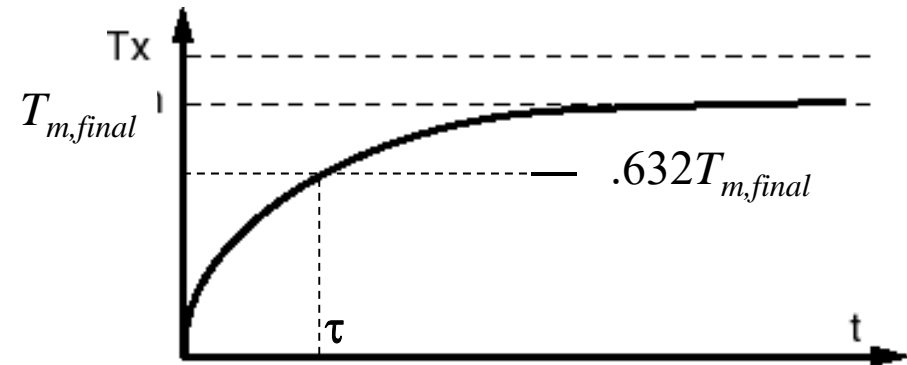
$$T_m = T_{m,final} (1 - e^{-t/\tau})$$

# 1<sup>st</sup> order system

$$T_m = T_{m,final} (1 - e^{-t/\tau})$$

$$T_{m,final} \text{ from condition } \frac{dT_m}{dt} = 0$$

$$T_{m,final} = \frac{G_{am} T_a + G_{xm} T_x}{G_{am} + G_{xm}} \quad \tau = \frac{C}{G_{xm} + G_{am}}$$



For  $T_{m,final}$  to be close to  $T_x$ :

$G_{xm}$  : as high as possible (good thermal contact sensor/object)

$G_{am}$  : as low as possible (bad contact sensor/ambient)

For fast measurements (low  $\tau$ ):

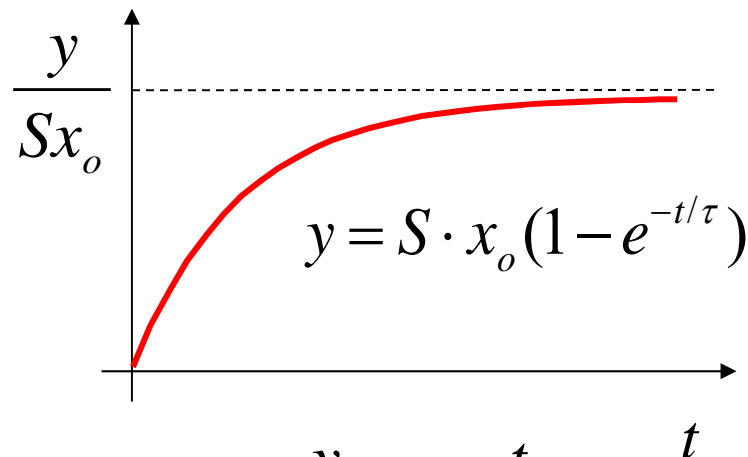
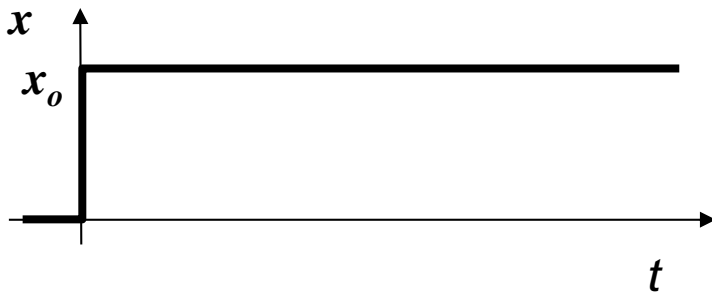
$C$  : as low as possible (small thermometer)

# How can we determine $S$ and $\tau$ ?

$$\tau \frac{dy}{dt} + y = S \cdot x$$

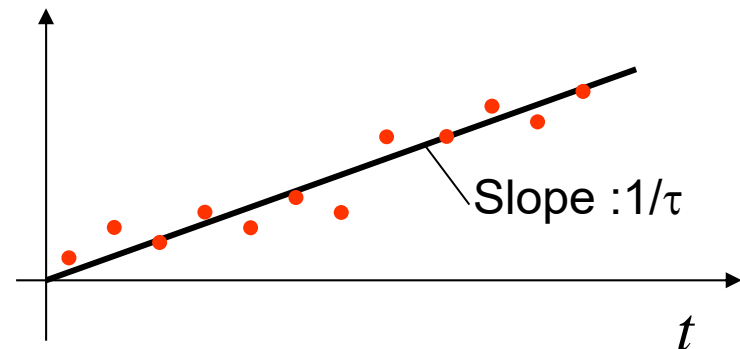
$S$  : static calibration (keep  $x$  constant, wait until  $y$  becomes constant)

$\tau$  : apply a stepwise change of input



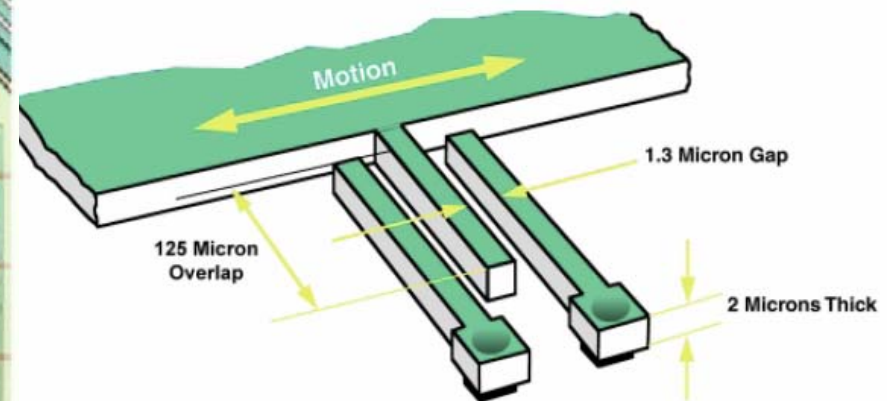
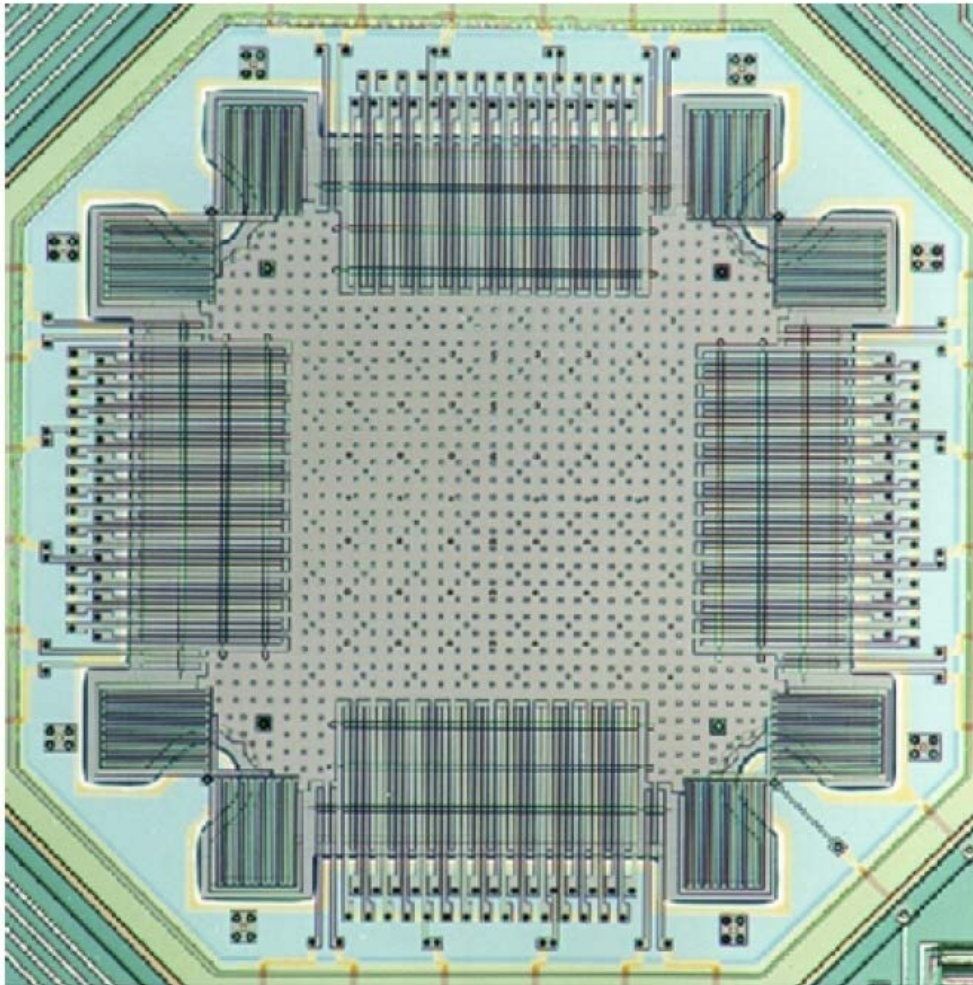
$$\ln\left(1 - \frac{y}{Sx_o}\right) = -\frac{t}{\tau}$$

$$-\ln\left(1 - \frac{y}{Sx_o}\right)$$



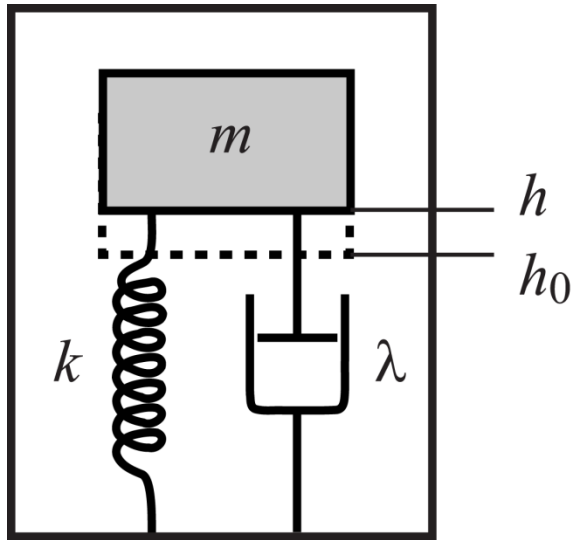
# 2<sup>nd</sup> order system: accelerometer

- MEMS (micro-electromechanical system) accelerometer



ADXL202 accelerometer  
[Analog Devices website](http://www.analog.com)

# 2<sup>nd</sup> order system: accelerometer



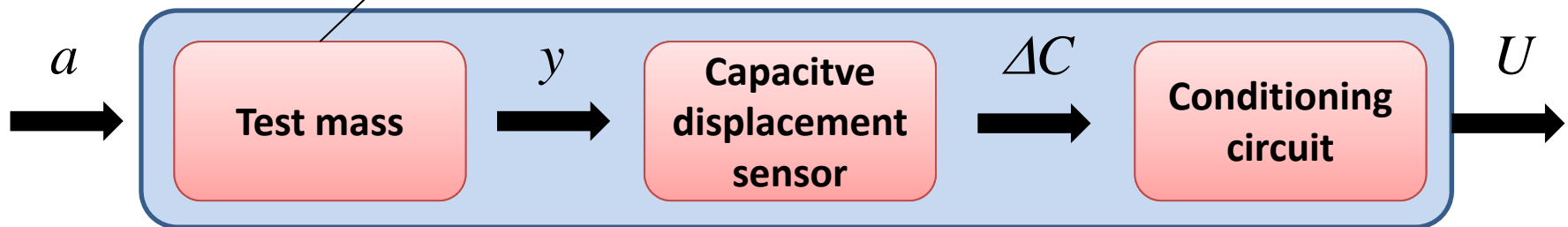
$h$  : position of the test mass

$h_0$  : position of the accelerometer (package)

$$y = h - h_0$$

$$\frac{1}{\omega_0^2} \frac{d^2 y}{dt^2} + \frac{2\xi}{\omega_0} \frac{dy}{dt} + y = S \cdot a$$

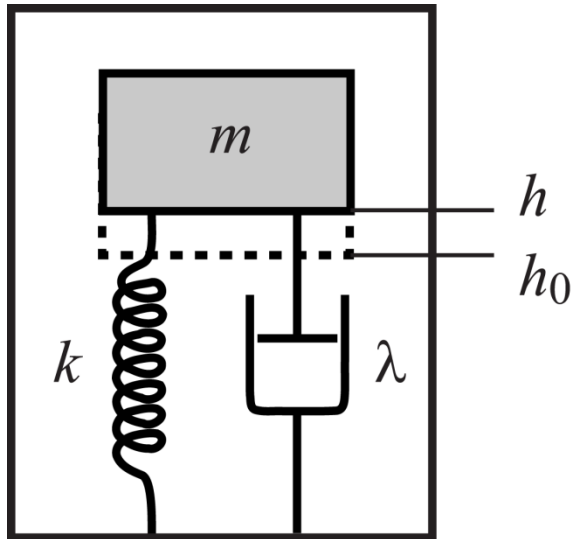
General equation for a 2<sup>nd</sup> order system



0 order

0 order

## 2<sup>nd</sup> order system



$$\frac{1}{\omega_0^2} \frac{d^2 y}{dt^2} + \frac{2\xi}{\omega_0} \frac{dy}{dt} + y = S \cdot a$$

$$a = -\frac{d^2 h_0}{dt^2}$$

Acceleration of the accelerometer package

$$\sum \vec{F} = m \vec{a}_M \quad y = h - h_0$$

$$S = \frac{m}{k} = \frac{1}{\omega_0^2}$$

$$\omega_0 = \sqrt{\frac{k}{m}}$$

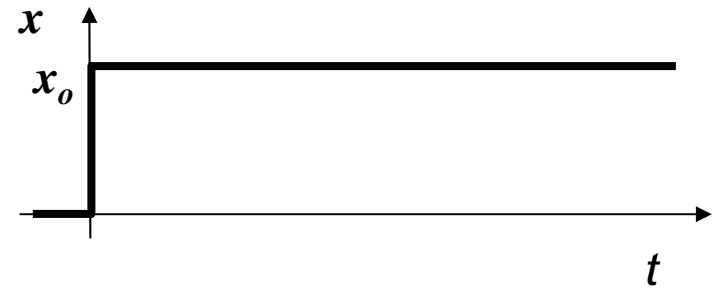
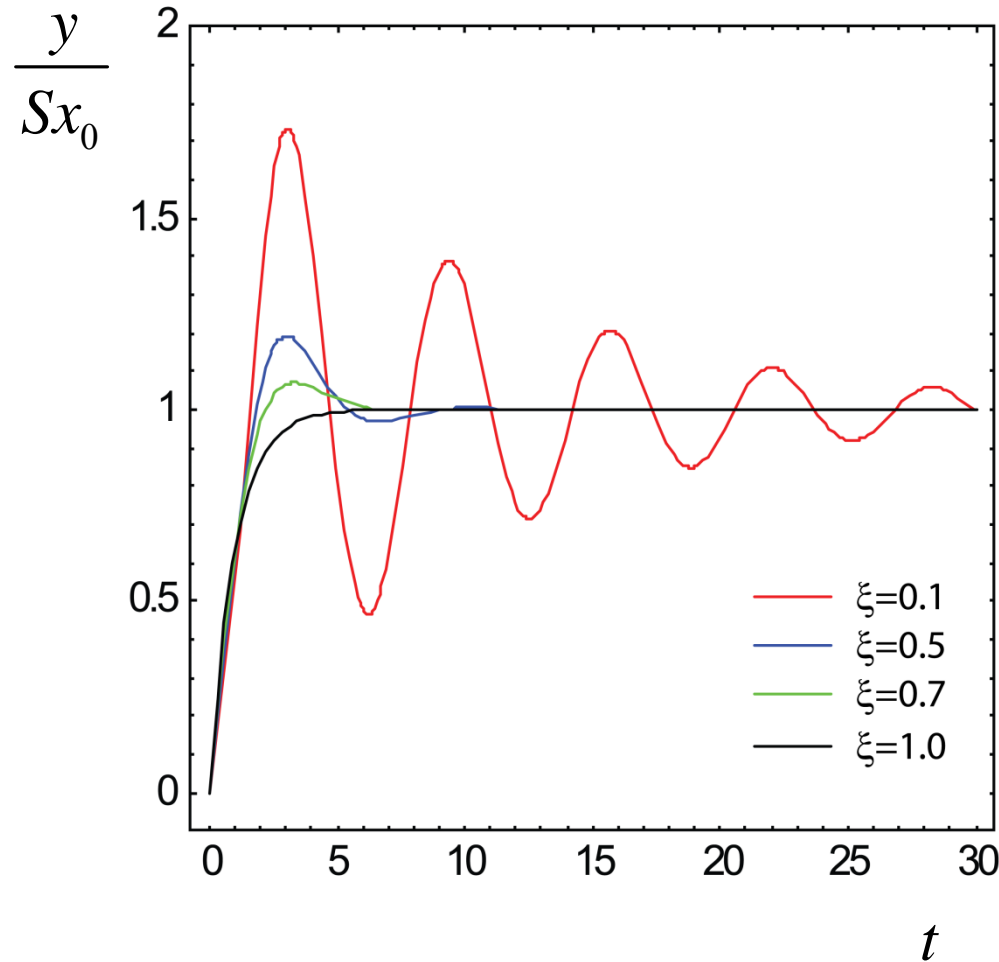
$$\xi = \frac{\lambda}{2\sqrt{km}}$$

$$\lambda \frac{dy}{dt} + ky = -m \frac{d^2 h}{dt^2}$$

$$m \frac{d^2 y}{dt^2} + \lambda \frac{dy}{dt} + ky = -m \frac{d^2 h_0}{dt^2}$$

# 2<sup>nd</sup> order system

- Response to a step change of input  $\frac{1}{\omega_0^2} \frac{d^2 y}{dt^2} + \frac{2\xi}{\omega_0} \frac{dy}{dt} + y = S \cdot x$



For  $\xi < 1$

$$\frac{y}{Sx_0} = 1 - \frac{e^{-\xi\omega_0 t}}{\sqrt{1-\xi^2}} \sin\left(\sqrt{1-\xi^2}\omega_0 t + \phi\right)$$

$$\phi = \text{Arc sin}\left(\sqrt{1-\xi^2}\right)$$



# 2<sup>nd</sup> order system

- Response to a step change of input

**overdamped**

$$\xi > 1$$

$$\frac{y}{Sx_o} = 1 + \frac{\xi - \sqrt{\xi^2 - 1}}{2\sqrt{\xi^2 - 1}} e^{-(\xi + \sqrt{\xi^2 - 1})\omega_o t} - \frac{\xi + \sqrt{\xi^2 - 1}}{2\sqrt{\xi^2 - 1}} e^{-(\xi - \sqrt{\xi^2 - 1})\omega_o t}$$

**critical damping**

$$\xi = 1$$

$$\frac{y}{Sx_o} = 1 - \omega_o t \cdot e^{-\omega_o t}$$

**underdamped**

$$\xi < 1$$

$$\frac{y}{Sx_o} = 1 - \frac{e^{-\xi\omega_o t}}{\sqrt{1 - \xi^2}} \sin\left(\sqrt{1 - \xi^2} \omega_o t + \varphi\right)$$

$$\text{with } \varphi = \text{Arc sin}\left(\sqrt{1 - \xi^2}\right)$$

# 2<sup>nd</sup> order system

- Response to pulsed change of input (pulse width  $\ll$  period of oscillations)

**overdamped**  
 $\xi > 1$

$$\frac{y}{Sx_o\omega_o} = \frac{e^{-\xi\omega_o t}}{\sqrt{\xi^2 - 1}} \sinh(\sqrt{\xi^2 - 1}\omega_o t)$$

**critical damping**  
 $\xi = 1$

$$\frac{y}{Sx_o\omega_o} = \omega_o t e^{-\omega_o t}$$

**underdamped**  
 $\xi < 1$

$$\frac{y}{Sx_o\omega_o} = \frac{e^{-\xi\omega_o t}}{\sqrt{1 - \xi^2}} \sin(\sqrt{1 - \xi^2}\omega_o t)$$

# How can we determine these parameters?

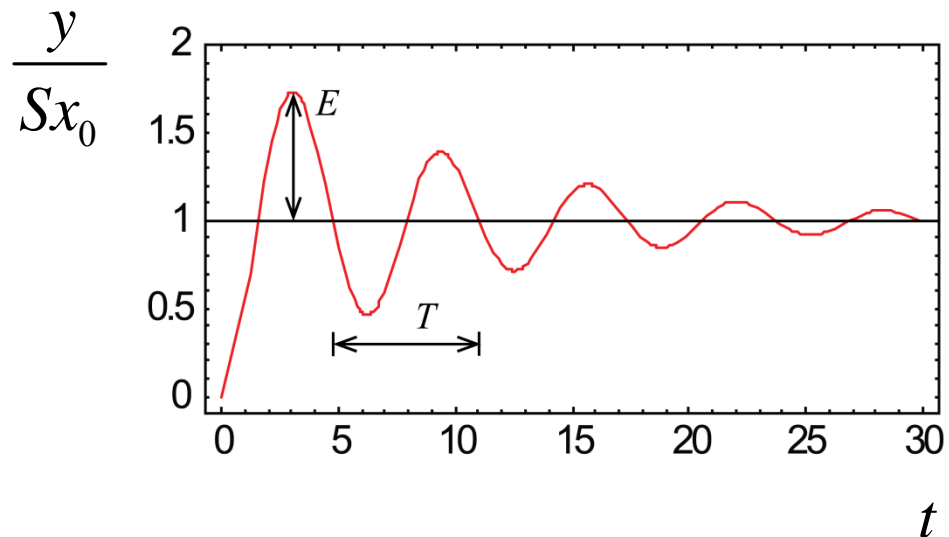
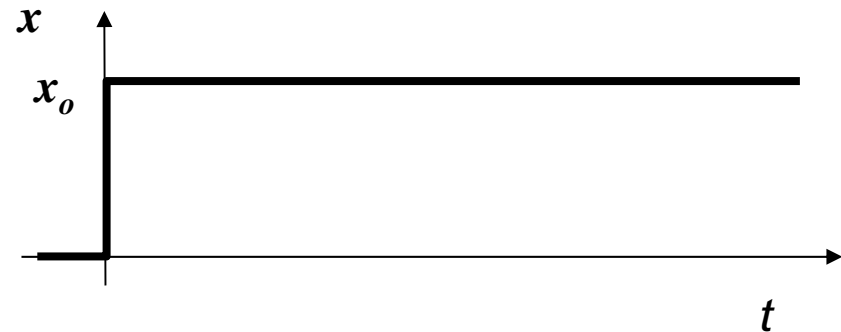
$S$  : static calibration (keep input constant, wait until output becomes constant)

$\omega_0$  and  $\xi$  : apply a step-wise change of the input

Other parameters:

Measure  $E$  (excursion)  
and  $T$  (period)

$$\frac{1}{\omega_0^2} \frac{d^2 y}{dt^2} + \frac{2\xi}{\omega_0} \frac{dy}{dt} + y = S \cdot x$$



# 2<sup>nd</sup> order system – stepped input

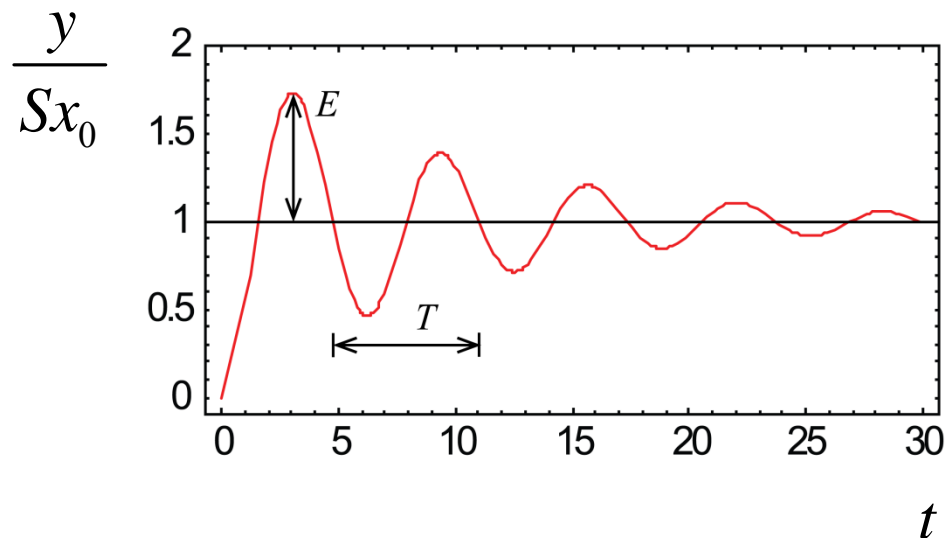
$$\frac{y}{Sx_o} = 1 - \frac{e^{-\xi\omega_o t}}{\sqrt{1-\xi^2}} \sin\left(\underbrace{\sqrt{1-\xi^2}\omega_o t + \varphi}_{\frac{2\pi}{T}}\right) \quad \omega_o = \frac{2\pi}{T\sqrt{1-\xi^2}}$$

Calculate  $\xi$ :

- find  $E$  from the condition  $\frac{d}{dt}\left(\frac{y}{Sx_o}\right) = 0$

$$\xi = \frac{1}{\sqrt{\left(\frac{\pi}{LnE}\right)^2 + 1}}$$

$$\omega_o = \frac{2\pi}{T\sqrt{1-\xi^2}}$$

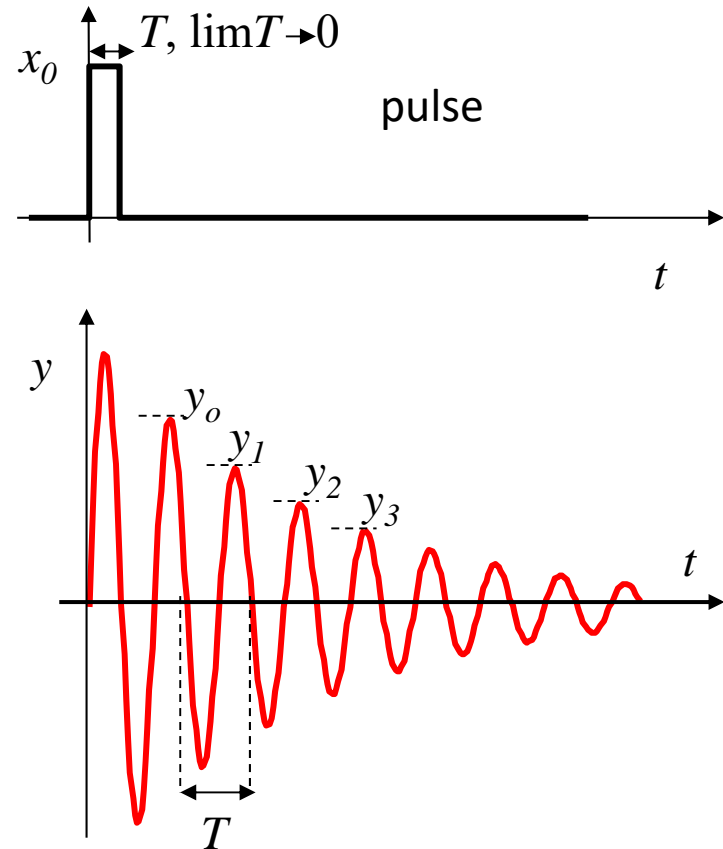


# 2<sup>nd</sup> order system – pulsed input

$$\frac{1}{\omega_0^2} \frac{d^2 y}{dt^2} + \frac{2\xi}{\omega_0} \frac{dy}{dt} + y = S \cdot x$$

$S$  : static calibration (keep input constant, wait until output becomes constant)  
 $\omega_0$  and  $\xi$  : apply a pulsed input

Measure  $y_0/y_i$  and  $T$



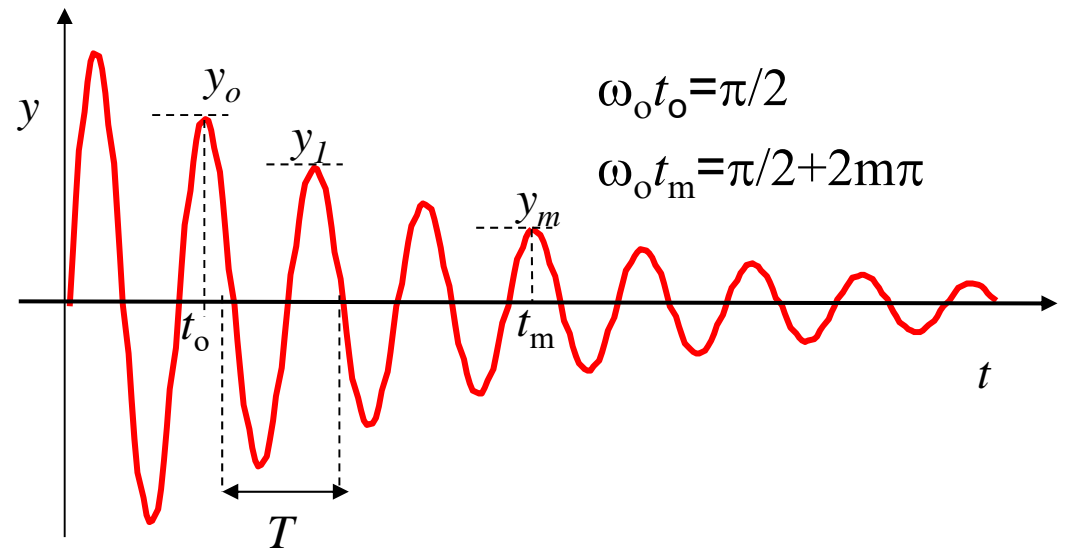
# 2<sup>nd</sup> order system – pulsed input

$$\frac{y}{Sx_o\omega_o} = \frac{e^{-\xi\omega_o t}}{\sqrt{1-\xi^2}} \sin\left(\underbrace{\sqrt{1-\xi^2}\omega_o t}_{\frac{2\pi}{T}}\right)$$

$$\omega_o = \frac{2\pi}{T\sqrt{1-\xi^2}} \quad \text{for } \xi < 1$$

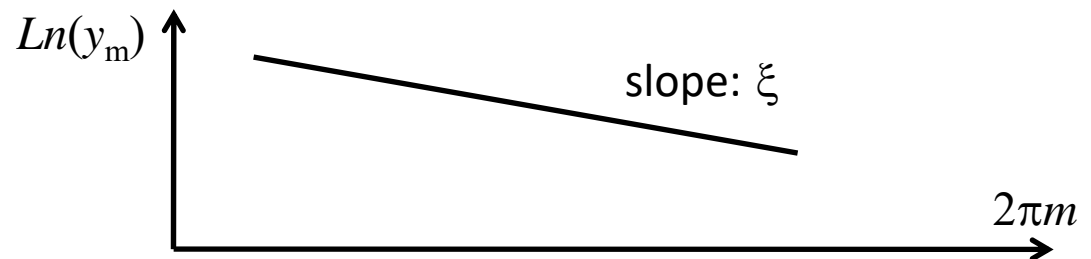
Calculating  $\xi$ : deduce  $y_i$  from the maxima of  $y$

$$\xi \approx \frac{\text{Ln} \frac{y_o}{y_m}}{2\pi m}$$



$$\text{Ln} y_m = \text{Ln} y_o - 2\pi m \xi$$

assuming  $\sqrt{1-\xi^2} \approx 1$



# 2<sup>nd</sup> order system – oscillating input

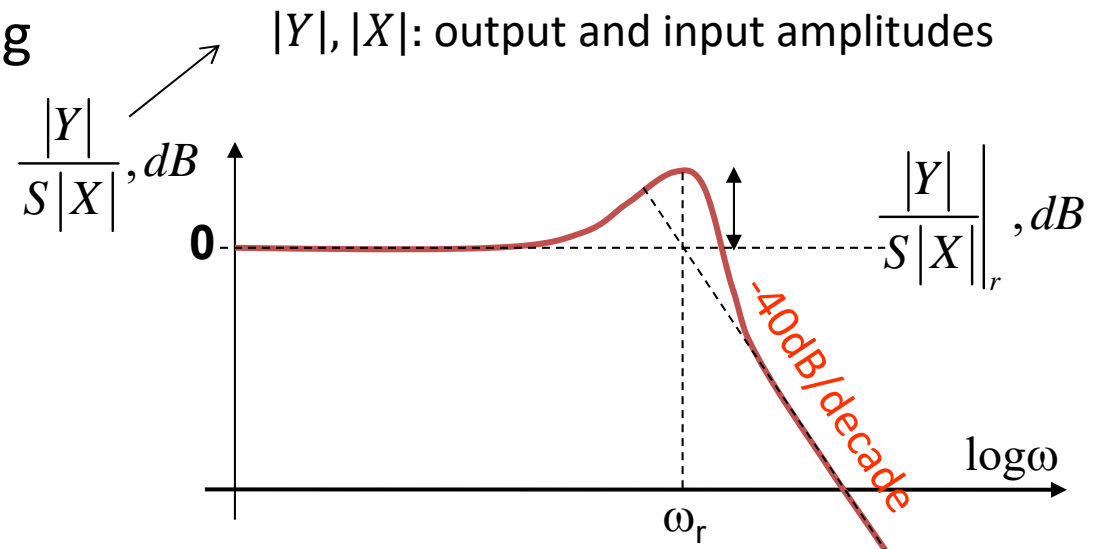
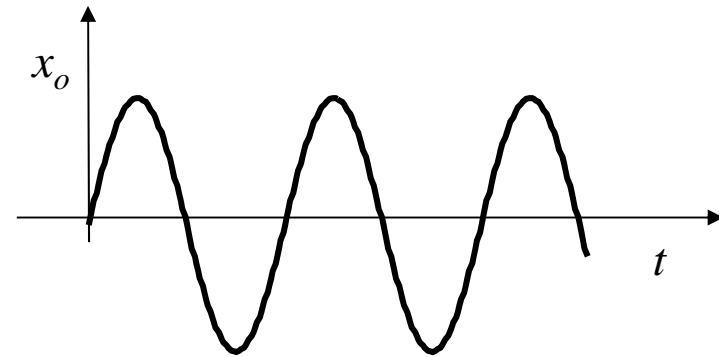
$$\frac{1}{\omega_0^2} \frac{d^2 y}{dt^2} + \frac{2\xi}{\omega_0} \frac{dy}{dt} + y = S \cdot x$$

$S$  : static calibration (keep input constant, wait until output becomes constant)

$\omega_0$  and  $\xi$  : apply an oscillating input with a variable frequency  $\omega$

Measure the maximum

$$\frac{|Y|}{S|X|} = \frac{1}{\sqrt{\left(1 - \frac{\omega^2}{\omega_0^2}\right)^2 + 4\xi^2 \frac{\omega^2}{\omega_0^2}}}$$



# 2<sup>nd</sup> order system – oscillating input

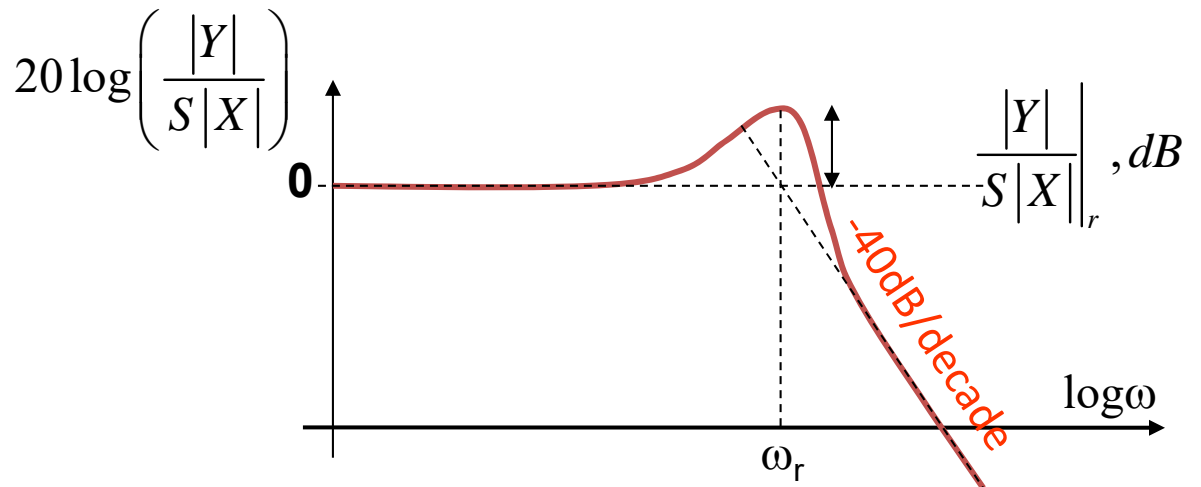
$$\frac{|Y|}{S|X|} = \frac{1}{\sqrt{\left(1 - \frac{\omega^2}{\omega_o^2}\right)^2 + 4\xi^2 \frac{\omega^2}{\omega_o^2}}}$$

$$\omega = \omega_r \text{ for } \frac{|Y|}{S|X|} = \max \text{ or } \left(1 - \frac{\omega^2}{\omega_o^2}\right)^2 + 4\xi^2 \frac{\omega^2}{\omega_o^2} = \min$$

$$\omega_0 = \frac{\omega_r}{\sqrt{1 - 2\xi^2}}$$

For  $\omega \gg \omega_r$

$$\frac{|Y|}{S|X|} \approx \frac{1}{\sqrt{\frac{\omega^4}{\omega_o^4} + 4\xi^2 \frac{\omega^2}{\omega_o^2}}} \approx \frac{\omega_o^2}{\omega^2}$$



$$20 \cdot \log(100) = 40$$



# Key points

- A measurement system is often modelled by a linear differential equation of the order 0, 1 or 2
- Static transfer parameters allow us to predict the measurement error
- The sensitivity and dynamic transfer parameters allow us to identify the order of the system